


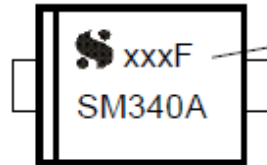
## Product/Process Change Notification

PCN#	Effective Date	Issue Date
2018-09-04C-01	Gradually changes from 2018/12/04	2018/9/4
PCN Classification		Product Category
Major		Diode
Subject		
Production process change from lead free to halogen free.		
Affected Product(s)		
Such as attachments.		
Description of Change(s)		
To meet EU environment requirement, we implement halogen free to our products.		
Content of Change(s)		
Adding "-C" to part number.		
Impact(s)		
None		
Attachment(s)		
SGS report. Reliability report.		

Approval		
Issue by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu

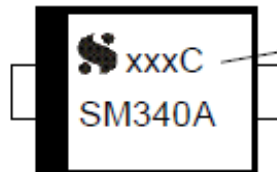
### Marking Code Description

#### Lead free Marking Code Description



Date Code:  
XXX = Date Code (149  
means Wk: 14, Yr: 2009)  
F = Lead Free

#### Halogen free Marking Code Description



Date Code:  
XXX = Date Code (149  
means Wk: 14, Yr: 2009)  
C = Halogen Free

**Affected Product(s)**

**SMA Package**

SM120A	SM4005A	SUF204A	SMA4757	SMA5947B	SMAJ400A	SMA6J40A	SMAJ300CA	SMA6J26CA
SM140A	SM4006A	SUF205A	SMA4758	SMA5948B	SMAJ40A	SMA6J43A	SMAJ30CA	SMA6J28CA
SM160A	SM4007A	ES25A	SMA4759	SMA5949B	SMAJ43A	SMA6J45A	SMAJ33CA	SMA6J30CA
SM1100A	QG5391A	SEF101A	SMA4760	SMA5950B	SMAJ440A	SMA6J48A	SMAJ350CA	SMA6J33CA
SM1200A	QG5392A	SEF102A	SMA4761	SMA5951B	SMAJ45A	SMA6J5.0A	SMAJ36CA	SMA6J36CA
SM1150A	QG5393A	SEF103A	SMA4762	SMA5952B	SMAJ48A	SMA6J51A	SMAJ400CA	SMA6J40CA
SM2150A	QG5395A	SEF104A	SMA4763	SMA5953B	SMAJ5.0A	SMA6J54A	SMAJ40CA	SMA6J43CA
SM220A	QG5397A	SEF105A	SMA4764	SMA5954B	SMAJ51A	SMA6J58A	SMAJ43CA	SMA6J45CA
SM240A	QG5398A	SEF106A	SMAZ1110	SMA5955B	SMAJ54A	SMA6J6.0A	SMAJ440CA	SMA6J48CA
SM260A	QG5399A	SEF107A	SMAZ1120	SMA5956B	SMAJ58A	SMA6J6.5A	SMAJ45CA	SMA6J5.0CA
SM2100A	QG201A	SEF105AS	SMAZ1130	SMAJ100A	SMAJ6.0A	SMA6J7.0A	SMAJ48CA	SMA6J51CA
SM2200A	QG202A	SEF201A	SMAZ1150	SMAJ10A	SMAJ6.5A	SMA6J7.5A	SMAJ5.0CA	SMA6J54CA
SM320A	QG203A	SEF202A	SMAZ1160	SMAJ110A	SMAJ60A	SMA6J8.0A	SMAJ51CA	SMA6J58CA
SM340A	QG204A	SEF203A	SMAZ1180	SMAJ11A	SMAJ64A	SMA6J8.5A	SMAJ54CA	SMA6J6.0CA
SM360A	QG205A	SEF204A	SMAZ1200	SMAJ120A	SMAJ7.0A	SMA6J9.0A	SMAJ58CA	SMA6J6.5CA
SM3100A	QG206A	SEF205A	SMAZ1300	SMAJ12A	SMAJ7.5A	SMAJ100CA	SMAJ6.0CA	SMA6J7.0CA
SM3200A	QG207A	SEF206A	SMA5920B	SMAJ130A	SMAJ70A	SMAJ10CA	SMAJ6.5CA	SMA6J7.5CA
SM3150A	SMF101A	SEF207A	SMA5921B	SMAJ13A	SMAJ75A	SMAJ110CA	SMAJ60CA	SMA6J8.0CA
SM520A	SMF102A	SMA4728	SMA5922B	SMAJ140A	SMAJ78A	SMAJ11CA	SMAJ64CA	SMA6J8.5CA
SM540A	SMF103A	SMA4733	SMA5923B	SMAJ14A	SMAJ8.0A	SMAJ120CA	SMAJ7.0CA	SMA6J9.0CA
SM560A	SMF104A	SMA4734	SMA5924B	SMAJ150A	SMAJ8.5A	SMAJ12CA	SMAJ7.5CA	
SM5150A	SMF105A	SMA4735	SMA5925B	SMAJ15A	SMAJ80A	SMAJ130CA	SMAJ70CA	
SM5100A	SMF106A	SMA4736	SMA5926B	SMAJ160A	SMAJ85A	SMAJ13CA	SMAJ75CA	
SK12L	SMF107A	SMA4737	SMA5927B	SMAJ16A	SMAJ9.0A	SMAJ140CA	SMAJ78CA	
SK12LL	SMF201A	SMA4738	SMA5928B	SMAJ170A	SMAJ90A	SMAJ14CA	SMAJ8.0CA	
SK12SL	SMF202A	SMA4739	SMA5929B	SMAJ17A	SMA6J10A	SMAJ150CA	SMAJ8.5CA	
SK14L	SMF203A	SMA4740	SMA5930B	SMAJ180A	SMA6J11A	SMAJ15CA	SMAJ80CA	
SK14LL	SMF204A	SMA4741	SMA5931B	SMAJ18A	SMA6J12A	SMAJ160CA	SMAJ85CA	
SK14SL	SMF205A	SMA4742	SMA5932B	SMAJ190A	SMA6J13A	SMAJ16CA	SMAJ9.0CA	
SK12AL	SMF206A	SMA4743	SMA5933B	SMAJ19A	SMA6J14A	SMAJ170CA	SMAJ90CA	
SK14AL	SMF207A	SMA4744	SMA5934B	SMAJ200A	SMA6J15A	SMAJ17CA	SMA6J10CA	
SK22L	SUF101A	SMA4745	SMA5935B	SMAJ20A	SMA6J16A	SMAJ180CA	SMA6J11CA	
SK22LL	SUF102A	SMA4746	SMA5936B	SMAJ220A	SMA6J17A	SMAJ18CA	SMA6J12CA	
SK24L	SUF103A	SMA4747	SMA5937B	SMAJ22A	SMA6J18A	SMAJ190CA	SMA6J13CA	
SK24LL	SUF104A	SMA4748	SMA5938B	SMAJ24A	SMA6J19A	SMAJ19CA	SMA6J14CA	
SK22AL	SUF105A	SMA4749	SMA5939B	SMAJ250A	SMA6J20A	SMAJ200CA	SMA6J15CA	
SK24AL	ES11A	SMA4750	SMA5940B	SMAJ26A	SMA6J22A	SMAJ20CA	SMA6J16CA	
SK26LL	ES12A	SMA4751	SMA5941B	SMAJ28A	SMA6J24A	SMAJ220CA	SMA6J17CA	
SK34LL	ES13A	SMA4752	SMA5942B	SMAJ300A	SMA6J26A	SMAJ22CA	SMA6J18CA	
SM4001A	ES14A	SMA4753	SMA5943B	SMAJ30A	SMA6J28A	SMAJ24CA	SMA6J19CA	
SM4002A	SUF201A	SMA4754	SMA5944B	SMAJ33A	SMA6J30A	SMAJ250CA	SMA6J20CA	
SM4003A	SUF202A	SMA4755	SMA5945B	SMAJ350A	SMA6J33A	SMAJ26CA	SMA6J22CA	
SM4004A	SUF203A	SMA4756	SMA5946B	SMAJ36A	SMA6J36A	SMAJ28CA	SMA6J24CA	

**Affected Product(s)**

**SMB Package**

SM120B	QG203B	ES45B	SMB5942B	SMB2EZ39D5	SMB3EZ5.1D5	SMB5371B	SMBJ30A	SMBJ190CA
SM140B	QG204B	SEF101B	SMB5943B	SMB2EZ43D5	SMB3EZ5.6D5	SMB5372B	SMBJ33A	SMBJ19CA
SM160B	QG205B	SEF102B	SMB5944B	SMB2EZ47D5	SMB3EZ5.1D5	SMB5373B	SMBJ350A	SMBJ200CA
SM1100B	QG206B	SEF103B	SMB5945B	SMB2EZ5.1D5	SMB3EZ5.6D5	SMB5374B	SMBJ36A	SMBJ20CA
SM1150B	QG207B	SEF104B	SMB5946B	SMB2EZ5.6D5	SMB3EZ6.2D5	SMB5375B	SMBJ400A	SMBJ220CA
SM1200B	QG301B	SEF105B	SMB5947B	SMB2EZ6.2D5	SMB3EZ6.8D5	SMB5376B	SMBJ40A	SMBJ22CA
SM220B	QG302B	SEF106B	SMB5948B	SMB2EZ6.8D5	SMB3EZ6.2D5	SMB5377B	SMBJ43A	SMBJ24CA
SM240B	QG303B	SEF107B	SMB5949B	SMB2EZ6.2D5	SMB3EZ6.8D5	SMB5378B	SMBJ440A	SMBJ250CA
SM260B	QG304B	SEF112B	SMB5950B	SMB2EZ6.8D5	SMB3EZ7.5D5	SMB5379B	SMBJ45A	SMBJ26CA
SM2100B	QG305B	SEF105B	SMB5951B	SMB2EZ7.5D5	SMB3EZ7.5D5	SMB5380B	SMBJ48A	SMBJ28CA
SM2200B	QG306B	SEF201B	SMB5952B	SMB2EZ7.5D5	SMB3EZ8.2D5	SMB5381B	SMBJ5.0A	SMBJ300CA
SM320B	QG307B	SEF202B	SMB5953B	SMB2EZ8.2D5	SMB3EZ8.2D5	SMB5382B	SMBJ51A	SMBJ30CA
SM340B	SMF101B	SEF203B	SMB5954B	SMB2EZ8.2D5	SMB3EZ9.1D5	SMB5383B	SMBJ54A	SMBJ33CA
SM360B	SMF102B	SEF204B	SMB5955B	SMB2EZ9.1D5	SMB3EZ9.1D5	SMB5384B	SMBJ58A	SMBJ350CA
SM3100B	SMF103B	SEF205B	SMB5956B	SMB2EZ9.1D5	SMB5338B	SMB5385B	SMBJ6.0A	SMBJ36CA
SM3150B	SMF104B	SEF206B	SMB2EZ100D5	SMB3EZ100D5	SMB5339B	SMB5386B	SMBJ6.5A	SMBJ400CA
SM3200B	SMF105B	SEF207B	SMB2EZ10D5	SMB3EZ10D5	SMB5340B	SMB5387B	SMBJ60A	SMBJ40CA
SMH3150B	SMF106B	SEF205B	SMB2EZ110D5	SMB3EZ110D5	SMB5341B	SMB5388B	SMBJ64A	SMBJ43CA
SM520B	SMF107B	SEF301B	SMB2EZ11D5	SMB3EZ11D5	SMB5342B	SMBJ100A	SMBJ7.0A	SMBJ440CA
SM540B	SMF201B	SEF302B	SMB2EZ120D5	SMB3EZ120D5	SMB5343B	SMBJ10A	SMBJ7.5A	SMBJ45CA
SM560B	SMF202B	SEF303B	SMB2EZ12D5	SMB3EZ12D5	SMB5344B	SMBJ110A	SMBJ70A	SMBJ48CA
SM5150B	SMF203B	SEF304B	SMB2EZ130D5	SMB3EZ130D5	SMB5345B	SMBJ11A	SMBJ75A	SMBJ5.0CA
SM5200B	SMF204B	SEF305B	SMB2EZ13D5	SMB3EZ13D5	SMB5346B	SMBJ120A	SMBJ78A	SMBJ51CA
SM5100B	SMF205B	SEF306B	SMB2EZ140D5	SMB3EZ140D5	SMB5347B	SMBJ12A	SMBJ8.0A	SMBJ54CA
SM820B	SMF206B	SEF305B	SMB2EZ14D5	SMB3EZ14D5	SMB5348B	SMBJ130A	SMBJ8.5A	SMBJ58CA
SM840B	SMF207B	SMB5920B	SMB2EZ150D5	SMB3EZ150D5	SMB5349B	SMBJ13A	SMBJ80A	SMBJ6.0CA
SM860B	SMF301B	SMB5921B	SMB2EZ15D5	SMB3EZ15D5	SMB5350B	SMBJ140A	SMBJ85A	SMBJ6.5CA
SM8100B	SMF302B	SMB5922B	SMB2EZ160D5	SMB3EZ160D5	SMB5351B	SMBJ14A	SMBJ9.0A	SMBJ60CA
SK12BL	SMF303B	SMB5923B	SMB2EZ16D5	SMB3EZ16D5	SMB5352B	SMBJ150A	SMBJ90A	SMBJ64CA
SK14BL	SMF304B	SMB5924B	SMB2EZ170D5	SMB3EZ170D5	SMB5353B	SMBJ15A	SMBJ100CA	SMBJ7.0CA
SK22BL	SMF305B	SMB5925B	SMB2EZ17D5	SMB3EZ17D5	SMB5354B	SMBJ160A	SMBJ10CA	SMBJ7.5CA
SK24BL	SMF306B	SMB5926B	SMB2EZ180D5	SMB3EZ180D5	SMB5355B	SMBJ16A	SMBJ110CA	SMBJ70CA
SK32BL	SMF307B	SMB5927B	SMB2EZ18D5	SMB3EZ18D5	SMB5356B	SMBJ170A	SMBJ11CA	SMBJ75CA
SK34BL	SUF201B	SMB5928B	SMB2EZ190D5	SMB3EZ190D5	SMB5357B	SMBJ17A	SMBJ120CA	SMBJ78CA
SK54BL	SUF202B	SMB5929B	SMB2EZ19D5	SMB3EZ19D5	SMB5358B	SMBJ180A	SMBJ12CA	SMBJ8.0CA
SK56BL	SUF203B	SMB5930B	SMB2EZ200D5	SMB3EZ200D5	SMB5359B	SMBJ18A	SMBJ130CA	SMBJ8.5CA
SK5200BL	SUF204B	SMB5931B	SMB2EZ20D5	SMB3EZ20D5	SMB5360B	SMBJ190A	SMBJ13CA	SMBJ80CA
SK5150B	SUF205B	SMB5932B	SMB2EZ220D5	SMB3EZ22D5	SMB5361B	SMBJ19A	SMBJ150CA	SMBJ85CA
SM4001B	ES21B	SMB5933B	SMB2EZ22D5	SMB3EZ24D5	SMB5362B	SMBJ200A	SMBJ14CA	SMBJ9.0CA
SM4002B	ES22B	SMB5934B	SMB2EZ24D5	SMB3EZ27D5	SMB5363B	SMBJ20A	SMBJ150CA	SMBJ90CA
SM4003B	ES23B	SMB5935B	SMB2EZ270D5	SMB3EZ28D5	SMB5364B	SMBJ220A	SMBJ15CA	
SM4004B	SUF206B	SMB5936B	SMB2EZ27D5	SMB3EZ30D5	SMB5365B	SMBJ22A	SMBJ160CA	
SM4005B	SUF301B	SMB5937B	SMB2EZ300D5	SMB3EZ33D5	SMB5366B	SMBJ24A	SMBJ16CA	
SM4006B	SUF302B	SMB5938B	SMB2EZ30D5	SMB3EZ36D5	SMB5367B	SMBJ250A	SMBJ170CA	
SM4007B	SUF303B	SMB5939B	SMB2EZ330D5	SMB3EZ39D5	SMB5368B	SMBJ26A	SMBJ17CA	
QG201B	SUF304B	SMB5940B	SMB2EZ33D5	SMB3EZ43D5	SMB5369B	SMBJ28A	SMBJ180CA	
QG202B	SUF305B	SMB5941B	SMB2EZ36D5	SMB3EZ47D5	SMB5370B	SMBJ300A	SMBJ18CA	



**Affected Product(s)**

**SMC Package**

SM320C	QG807C	SMC5345B	SMCJ130A	SMDJ10A	5SMDJ13A	SMCJ24CA	SMDJ18CA	5SMDJ40CA
SM340C	SMF212C	SMC5346B	SMCJ13A	SMDJ110A	5SMDJ14A	SMCJ250CA	SMDJ190CA	5SMDJ43CA
SM360C	SMF301C	SMC5347B	SMCJ14A	SMDJ11A	5SMDJ15A	SMCJ26CA	SMDJ20CA	5SMDJ45CA
SM3100C	SMF302C	SMC5348B	SMCJ150A	SMDJ120A	5SMDJ16A	SMCJ28CA	SMDJ22CA	5SMDJ48CA
SM3150C	SMF303C	SMC5349B	SMCJ15A	SMDJ12A	5SMDJ17A	SMCJ300CA	SMDJ24CA	5SMDJ51CA
SM3200C	SMF304C	SMC5350B	SMCJ160A	SMDJ130A	5SMDJ18A	SMCJ30CA	SMDJ26CA	5SMDJ54CA
SM520C	SMF305C	SMC5351B	SMCJ16A	SMDJ13A	5SMDJ19A	SMCJ33CA	SMDJ28CA	5SMDJ58CA
SM540C	SMF306C	SMC5352B	SMCJ17A	SMDJ14A	5SMDJ20A	SMCJ350CA	SMDJ30CA	5SMDJ60CA
SM560C	SMF307C	SMC5353B	SMCJ180A	SMDJ150A	5SMDJ22A	SMCJ36CA	SMDJ33CA	5SMDJ64CA
SM5150C	SMF504C	SMC5354B	SMCJ18A	SMDJ15A	5SMDJ24A	SMCJ400CA	SMDJ36CA	5SMDJ70CA
SM5200C	SMF503C	SMC5355B	SMCJ190A	SMDJ160A	5SMDJ26A	SMCJ40CA	SMDJ40CA	5SMDJ75CA
SM5100C	SMF502C	SMC5356B	SMCJ200A	SMDJ16A	5SMDJ28A	SMCJ43CA	SMDJ43CA	5SMDJ78CA
SM820C	SMF501C	SMC5357B	SMCJ20A	SMDJ170A	5SMDJ30A	SMCJ440CA	SMDJ45CA	5SMDJ80CA
SM840C	SMF505C	SMC5358B	SMCJ220A	SMDJ17A	5SMDJ33A	SMCJ45CA	SMDJ48CA	5SMDJ85CA
SM860C	SMF506C	SMC5359B	SMCJ22A	SMDJ180A	5SMDJ36A	SMCJ48CA	SMDJ5.0CA	
SM8100C	SMF507C	SMC5360B	SMCJ24A	SMDJ18A	5SMDJ40A	SMCJ5.0CA	SMDJ51CA	
SM8200C	SUF301C	SMC5361B	SMCJ250A	SMDJ190A	5SMDJ43A	SMCJ51CA	SMDJ54CA	
SM8150C	SUF302C	SMC5362B	SMCJ26A	SMDJ20A	5SMDJ45A	SMCJ54CA	SMDJ58CA	
SM1040C	SUF303C	SMC5363B	SMCJ28A	SMDJ22A	5SMDJ48A	SMCJ58CA	SMDJ6.0CA	
SM10100C	SUF304C	SMC5364B	SMCJ300A	SMDJ24A	5SMDJ51A	SMCJ6.0CA	SMDJ6.5CA	
SM10150C	SUF305C	SMC5365B	SMCJ30A	SMDJ26A	5SMDJ54A	SMCJ6.5CA	SMDJ60CA	
SM10200C	SUF501C	SMC5366B	SMCJ33A	SMDJ28A	5SMDJ58A	SMCJ60CA	SMDJ64CA	
SM1020C	SUF502C	SMC5367B	SMCJ350A	SMDJ30A	5SMDJ60A	SMCJ64CA	SMDJ7.0CA	
SM1060C	SUF503C	SMC5368B	SMCJ36A	SMDJ33A	5SMDJ64A	SMCJ7.0CA	SMDJ7.5CA	
SK32CL	SUF504C	SMC5369B	SMCJ400A	SMDJ36A	5SMDJ70A	SMCJ7.5CA	SMDJ70CA	
SK34CL	SUF505C	SMC5370B	SMCJ40A	SMDJ40A	5SMDJ75A	SMCJ70CA	SMDJ75CA	
SK5100C	ES45C	SMC5371B	SMCJ43A	SMDJ43A	5SMDJ78A	SMCJ75CA	SMDJ78CA	
SK1045CL	SEF112C	SMC5372B	SMCJ440A	SMDJ45A	5SMDJ80A	SMCJ78CA	SMDJ8.0CA	
QG301C	SEF301C	SMC5373B	SMCJ45A	SMDJ48A	5SMDJ85A	SMCJ8.0CA	SMDJ8.5CA	
QG302C	SEF302C	SMC5374B	SMCJ48A	SMDJ5.0A	SMCJ10CA	SMCJ8.5CA	SMDJ85CA	
QG303C	SEF303C	SMC5375B	SMCJ5.0A	SMDJ51A	SMCJ110CA	SMCJ85CA	SMDJ9.0CA	
QG304C	SEF304C	SMC5376B	SMCJ51A	SMDJ54A	SMCJ11CA	SMCJ9.0CA	SMDJ90CA	
QG305C	SEF305C	SMC5377B	SMCJ54A	SMDJ58A	SMCJ120CA	SMCJ90CA	5SMDJ11CA	
QG306C	SEF306C	SMC5378B	SMCJ58A	SMDJ6.0A	SMCJ12CA	SMDJ100CA	5SMDJ12CA	
QG307C	SEF307C	SMC5379B	SMCJ6.0A	SMDJ6.5A	SMCJ130CA	SMDJ10CA	5SMDJ13CA	
QG308C	SEF501C	SMC5380B	SMCJ6.5A	SMDJ60A	SMCJ13CA	SMDJ110CA	5SMDJ14CA	
QG501C	SEF502C	SMC5381B	SMCJ60A	SMDJ64A	SMCJ14CA	SMDJ11CA	5SMDJ15CA	
QG502C	SEF503C	SMC5382B	SMCJ64A	SMDJ7.0A	SMCJ150CA	SMDJ120CA	5SMDJ16CA	
QG503C	SEF504C	SMC5383B	SMCJ7.0A	SMDJ7.5A	SMCJ15CA	SMDJ12CA	5SMDJ17CA	
QG504C	SEF505C	SMC5384B	SMCJ7.5A	SMDJ70A	SMCJ160CA	SMDJ130CA	5SMDJ18CA	
QG505C	SEF506C	SMC5385B	SMCJ70A	SMDJ75A	SMCJ16CA	SMDJ13CA	5SMDJ19CA	
QG506C	SEF507C	SMC5386B	SMCJ75A	SMDJ78A	SMCJ17CA	SMDJ14CA	5SMDJ20CA	
QG507C	SMC5338B	SMC5387B	SMCJ78A	SMDJ8.0A	SMCJ180CA	SMDJ150CA	5SMDJ22CA	
QG801C	SMC5339B	SMC5388B	SMCJ8.0A	SMDJ8.5A	SMCJ18CA	SMDJ15CA	5SMDJ24CA	
QG802C	SMC5340B	SMCJ10A	SMCJ8.5A	SMDJ85A	SMCJ190CA	SMDJ160CA	5SMDJ26CA	
QG803C	SMC5341B	SMCJ110A	SMCJ85A	SMDJ9.0A	SMCJ200CA	SMDJ16CA	5SMDJ28CA	
QG804C	SMC5342B	SMCJ11A	SMCJ9.0A	SMDJ90A	SMCJ20CA	SMDJ170CA	5SMDJ30CA	
QG805C	SMC5343B	SMCJ120A	SMCJ90A	5SMDJ11A	SMCJ220CA	SMDJ17CA	5SMDJ33CA	
QG806C	SMC5344B	SMCJ12A	SMDJ100A	5SMDJ12A	SMCJ22CA	SMDJ180CA	5SMDJ36CA	



## Reliability Testing Summary Report

Date: 2018/08/31

Document No.: SL18-07-340A

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SM340A-C	100±5°C, 80% VR, T=1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SM340A-C	150°C, T=1000hrs		77	0	0	ACC
PCT Pressure Cooker Test	SM340A-C	121°C, 29.7PSIG, 168hrs		77	0	0	ACC
TCT Temperature Cycle Test	SM340A-C	-55°C/30min, 150°C/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SM340A-C	85 ± 2°C, RH=85±5%, 1000hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SM340A-C	85 ± 2°C, RH=85±5%, 80% VR, 1000hrs		77	0	0	ACC
Solderability	SM340A-C	245 ± 5°C, 5Sec the inspected area of each lead must have 95% solder coverage minimum		10	0	0	ACC

**Judgment:**

qualified     unqualified

Testing Start Date: 2018.07.01    Testing End Date: 2018.08.31

Tester: King Huang    Approval: Peter Yang



## Electrical Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 25°C

Test Date: 2018.07.02

Test Standard : Specifications

Operator: Joe Lee

Test Result: PASS

No	VF (mV)	VBR (V)	IR (uA)
1	477mV	50.9V	8.448uA
2	477mV	51.5V	6.996uA
3	477mV	51.3V	5.768uA
4	476mV	52.1V	8.406uA
5	479mV	51.7V	6.581uA
6	476mV	49.8V	9.178uA
7	476mV	51.4V	5.805uA
8	478mV	51.4V	8.558uA
9	477mV	49.9V	5.757uA
10	478mV	50.1V	6.440uA
11	478mV	51.2V	6.273uA
12	477mV	50.4V	5.751uA
13	477mV	51.8V	5.979uA
14	478mV	52.0V	7.984uA
15	477mV	51.0V	8.615uA
16	478mV	53.0V	8.257uA
17	477mV	50.2V	7.621uA
18	477mV	51.7V	6.408uA
19	476mV	52.0V	7.123uA
20	479mV	50.8V	8.543uA
21	476mV	52.5V	7.294uA
22	476mV	51.0V	9.859uA
23	477mV	50.3V	9.431uA
24	477mV	52.5V	7.464uA
25	476mV	52.0V	7.757uA
26	476mV	51.5V	6.484uA
27	480mV	53.1V	6.930uA
28	476mV	53.5V	9.087uA
29	479mV	53.6V	9.578uA
30	476mV	52.1V	7.290uA
31	478mV	50.4V	6.002uA
32	479mV	53.4V	6.206uA
33	477mV	51.9V	7.891uA
34	480mV	53.2V	7.353uA
35	476mV	50.4V	7.829uA



## Electrical Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 25°C

Test Date: 2018.07.02

Test Standard : Specifications

Operator: Joe Lee

Test Result: PASS

No	VF (mV)	VBR (V)	IR (uA)
36	480mV	50.2V	6.030uA
37	480mV	53.2V	8.836uA
38	477mV	51.3V	8.642uA
39	479mV	51.9V	8.107uA
40	480mV	50.6V	9.187uA
41	477mV	50.4V	8.816uA
42	477mV	52.8V	7.718uA
43	479mV	51.5V	5.997uA
44	476mV	52.8V	9.003uA
45	476mV	51.5V	6.559uA
46	478mV	50.3V	7.447uA
47	480mV	52.1V	5.617uA
48	480mV	52.0V	6.825uA
49	481mV	51.9V	7.814uA
50	480mV	53.7V	8.588uA
51	480mV	50.2V	9.185uA
52	476mV	50.9V	8.077uA
53	478mV	52.0V	8.832uA
54	476mV	50.3V	8.107uA
55	478mV	49.9V	7.191uA
56	479mV	53.3V	6.704uA
57	478mV	50.2V	8.244uA
58	480mV	51.5V	8.867uA
59	476mV	50.4V	7.137uA
60	479mV	52.0V	6.438uA
61	478mV	53.3V	8.129uA
62	478mV	51.2V	6.570uA
63	479mV	50.5V	7.274uA
64	478mV	53.0V	7.708uA
65	478mV	51.4V	8.802uA
66	480mV	49.9V	7.727uA
67	477mV	53.0V	7.721uA
68	480mV	51.6V	9.229uA
69	477mV	50.2V	7.656uA
70	478mV	51.6V	6.371uA





# SeCoS Corporation

## Electrical Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 25°C

Test Date: 2018.07.02

Test Standard : Specifications

Operator: Joe Lee

Test Result: PASS

No	VF (mV)	VBR (V)	IR (uA)
71	479mV	50.8V	8.351uA
72	479mV	51.5V	6.371uA
73	476mV	52.7V	8.170uA
74	478mV	50.6V	9.013uA
75	480mV	51.1V	9.034uA
76	481mV	51.7V	9.628uA
77	477mV	49.7V	6.383uA

Made By: King Huang

Approval: Peter Yang



## High Temperature Reverse Bias Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 100±5°C , 80% VR, T=1000hrs

Test Date: 2018.07.03 ~ 2018.08.14

Test Standard : JESD22 STANDER Method-A108

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	480mV	50.8V	8.189uA	479mV	51.5V	7.991uA
2	479mV	53.3V	7.834uA	478mV	52.4V	9.606uA
3	480mV	50.3V	8.158uA	479mV	52.7V	8.627uA
4	476mV	51.4V	8.615uA	481mV	51.3V	6.735uA
5	479mV	52.9V	8.276uA	476mV	50.1V	9.588uA
6	479mV	52.7V	6.251uA	478mV	49.8V	8.746uA
7	478mV	51.6V	8.717uA	480mV	53.5V	6.735uA
8	481mV	50.4V	8.596uA	476mV	53.7V	9.375uA
9	476mV	51.3V	7.184uA	480mV	52.6V	5.696uA
10	479mV	49.9V	9.585uA	477mV	50.7V	7.723uA
11	481mV	52.7V	8.117uA	478mV	51.9V	8.304uA
12	479mV	53.2V	6.541uA	479mV	51.3V	7.810uA
13	480mV	51.4V	8.399uA	478mV	53.6V	9.110uA
14	477mV	51.4V	7.285uA	480mV	52.7V	7.723uA
15	479mV	50.3V	8.817uA	480mV	53.5V	6.918uA
16	480mV	51.6V	7.469uA	478mV	50.8V	6.391uA
17	477mV	52.9V	7.706uA	480mV	50.5V	9.781uA
18	480mV	52.3V	8.462uA	479mV	53.2V	8.447uA
19	476mV	51.4V	9.491uA	476mV	51.5V	8.910uA
20	481mV	53.5V	5.784uA	480mV	53.7V	9.595uA
21	480mV	52.6V	7.957uA	476mV	50.6V	6.195uA
22	479mV	53.1V	5.686uA	480mV	49.8V	8.549uA
23	480mV	50.1V	7.104uA	480mV	51.0V	6.512uA
24	481mV	52.6V	7.673uA	480mV	53.5V	6.738uA
25	477mV	53.6V	7.002uA	476mV	51.8V	8.759uA
26	477mV	50.9V	5.747uA	478mV	52.5V	7.252uA
27	480mV	49.9V	7.197uA	478mV	52.3V	6.359uA
28	480mV	50.2V	6.138uA	477mV	52.6V	9.200uA
29	477mV	50.0V	8.501uA	477mV	53.3V	7.024uA
30	479mV	52.6V	9.822uA	480mV	52.9V	6.791uA
31	478mV	50.4V	8.748uA	477mV	49.9V	7.762uA
32	477mV	50.4V	6.511uA	477mV	52.7V	9.140uA
33	476mV	53.1V	6.563uA	480mV	52.3V	5.896uA
34	476mV	50.2V	7.859uA	479mV	53.4V	7.526uA



## High Temperature Reverse Bias Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 100±5°C , 80% VR, T=1000hrs

Test Date: 2018.07.03 ~ 2018.08.14

Test Standard : JESD22 STANDER Method-A108

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	476mV	53.5V	7.446uA	478mV	53.5V	6.927uA
36	477mV	52.3V	9.879uA	480mV	50.5V	9.772uA
37	480mV	51.5V	9.403uA	476mV	49.8V	9.456uA
38	476mV	51.4V	7.153uA	479mV	50.9V	9.515uA
39	477mV	52.4V	6.426uA	479mV	52.5V	9.387uA
40	477mV	49.8V	7.851uA	479mV	51.4V	9.047uA
41	479mV	52.8V	8.505uA	478mV	50.8V	8.840uA
42	478mV	51.4V	6.951uA	480mV	51.8V	9.502uA
43	481mV	51.6V	9.696uA	478mV	52.4V	7.920uA
44	480mV	51.6V	9.066uA	477mV	51.6V	8.165uA
45	480mV	49.8V	6.354uA	479mV	53.4V	5.814uA
46	478mV	49.9V	8.996uA	477mV	51.3V	8.585uA
47	481mV	50.3V	9.450uA	477mV	51.5V	7.991uA
48	477mV	50.2V	8.075uA	479mV	50.8V	7.647uA
49	479mV	51.1V	8.196uA	479mV	51.9V	8.802uA
50	477mV	53.5V	5.655uA	479mV	50.1V	5.638uA
51	480mV	53.2V	8.701uA	480mV	53.6V	9.364uA
52	477mV	51.4V	8.113uA	479mV	51.4V	8.040uA
53	476mV	49.9V	7.629uA	481mV	50.4V	8.508uA
54	476mV	51.5V	8.511uA	477mV	50.4V	7.633uA
55	479mV	52.7V	9.736uA	476mV	52.0V	8.530uA
56	477mV	50.2V	9.260uA	476mV	51.8V	9.525uA
57	479mV	50.9V	9.431uA	480mV	52.7V	9.383uA
58	479mV	51.6V	8.952uA	476mV	49.9V	8.706uA
59	476mV	53.6V	6.250uA	476mV	50.8V	9.533uA
60	479mV	52.5V	8.493uA	479mV	50.4V	6.694uA
61	479mV	50.2V	6.168uA	476mV	53.4V	9.760uA
62	476mV	51.8V	7.659uA	481mV	50.9V	8.845uA
63	479mV	49.8V	8.984uA	479mV	50.3V	9.835uA
64	480mV	53.3V	9.837uA	479mV	50.1V	5.839uA
65	479mV	51.5V	9.016uA	479mV	52.4V	9.430uA
66	478mV	50.2V	7.437uA	477mV	52.1V	7.154uA
67	476mV	50.8V	9.192uA	478mV	50.7V	6.875uA
68	476mV	52.8V	9.834uA	477mV	49.8V	6.315uA



# SeCoS Corporation

## High Temperature Reverse Bias Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 100±5°C , 80% VR, T=1000hrs

Test Date: 2018.07.03 ~ 2018.08.14

Test Standard : JESD22 STANDER Method-A108

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	478mV	53.5V	9.721uA	480mV	51.1V	8.841uA
70	481mV	53.2V	9.287uA	478mV	50.7V	8.432uA
71	476mV	53.7V	8.689uA	478mV	50.6V	5.909uA
72	480mV	52.1V	5.866uA	480mV	53.2V	9.036uA
73	481mV	51.1V	6.062uA	480mV	53.2V	9.254uA
74	479mV	53.0V	7.732uA	478mV	50.7V	6.664uA
75	480mV	52.7V	6.709uA	480mV	53.5V	8.668uA
76	478mV	52.5V	6.069uA	476mV	52.0V	5.953uA
77	477mV	53.6V	7.000uA	480mV	50.1V	9.376uA

Made By: King Huang

Approval: Peter Yang





# SeCoS Corporation

## High Temperature Storage Life Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 150°C, T=1000hrs

Test Date: 2018.07.04 ~ 2018.08.15

Test Standard : JESD22 STANDER Method-A103

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	480mV	52.8V	5.700uA	477mV	52.2V	8.661uA
2	479mV	50.2V	6.583uA	480mV	52.4V	9.642uA
3	476mV	51.5V	6.907uA	477mV	51.7V	8.716uA
4	477mV	53.2V	8.129uA	479mV	52.7V	6.702uA
5	476mV	52.7V	9.708uA	477mV	52.9V	6.322uA
6	478mV	49.8V	7.054uA	478mV	51.8V	6.609uA
7	479mV	50.0V	5.873uA	479mV	51.8V	9.839uA
8	480mV	52.0V	9.082uA	481mV	53.5V	6.244uA
9	480mV	51.7V	6.781uA	479mV	53.6V	8.094uA
10	480mV	50.9V	8.607uA	479mV	51.8V	5.952uA
11	477mV	52.7V	8.725uA	478mV	50.8V	6.806uA
12	479mV	53.0V	8.157uA	480mV	50.7V	8.187uA
13	478mV	52.5V	7.331uA	479mV	52.0V	9.843uA
14	478mV	52.7V	6.010uA	478mV	51.3V	8.646uA
15	478mV	51.2V	5.741uA	480mV	50.4V	5.821uA
16	479mV	50.5V	6.384uA	477mV	51.9V	8.904uA
17	476mV	50.9V	8.389uA	478mV	51.0V	6.898uA
18	477mV	52.4V	8.675uA	480mV	50.7V	8.558uA
19	478mV	49.8V	7.724uA	479mV	51.0V	9.087uA
20	478mV	52.8V	7.054uA	478mV	51.3V	8.914uA
21	478mV	51.9V	6.695uA	478mV	52.6V	6.296uA
22	480mV	51.5V	6.180uA	477mV	50.7V	7.537uA
23	480mV	53.3V	7.383uA	478mV	50.6V	6.328uA
24	480mV	51.3V	6.866uA	479mV	51.7V	9.032uA
25	477mV	50.3V	8.156uA	481mV	51.8V	8.023uA
26	478mV	50.4V	6.187uA	479mV	52.0V	8.002uA
27	478mV	52.4V	6.281uA	477mV	51.7V	6.341uA
28	479mV	51.8V	9.612uA	476mV	51.6V	6.311uA
29	476mV	51.7V	9.440uA	476mV	52.5V	8.154uA
30	476mV	50.6V	8.000uA	478mV	50.3V	6.831uA
31	478mV	50.9V	6.748uA	480mV	50.1V	6.294uA
32	480mV	51.8V	6.213uA	479mV	52.7V	6.585uA
33	477mV	50.3V	9.366uA	476mV	51.9V	8.412uA
34	481mV	50.6V	7.696uA	477mV	50.6V	7.172uA



## High Temperature Storage Life Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 150°C, T=1000hrs

Test Date: 2018.07.04 ~ 2018.08.15

Test Standard : JESD22 STANDER Method-A103

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	479mV	53.0V	6.319uA	478mV	50.6V	8.669uA
36	480mV	53.4V	6.944uA	476mV	53.1V	6.097uA
37	477mV	49.9V	9.772uA	478mV	52.6V	6.866uA
38	480mV	50.4V	9.579uA	476mV	50.0V	6.629uA
39	479mV	50.7V	7.307uA	478mV	52.1V	6.130uA
40	478mV	50.8V	9.358uA	479mV	52.5V	9.587uA
41	478mV	53.0V	8.668uA	480mV	50.2V	8.686uA
42	480mV	53.3V	9.205uA	478mV	50.7V	8.141uA
43	478mV	50.9V	6.109uA	477mV	50.7V	7.652uA
44	478mV	52.9V	6.160uA	476mV	50.6V	7.718uA
45	477mV	50.9V	9.341uA	477mV	52.9V	6.582uA
46	478mV	50.6V	7.554uA	480mV	50.6V	5.895uA
47	479mV	53.2V	9.475uA	480mV	49.8V	7.542uA
48	476mV	52.2V	5.710uA	481mV	51.5V	5.742uA
49	479mV	50.2V	7.298uA	477mV	50.3V	8.510uA
50	480mV	51.2V	7.745uA	480mV	51.9V	7.415uA
51	480mV	50.4V	7.567uA	479mV	52.9V	8.065uA
52	476mV	52.9V	7.613uA	479mV	51.7V	5.678uA
53	479mV	52.0V	6.616uA	477mV	51.0V	7.186uA
54	478mV	53.1V	6.175uA	478mV	51.2V	6.961uA
55	481mV	53.4V	8.193uA	478mV	52.4V	8.351uA
56	479mV	53.7V	8.914uA	480mV	49.9V	8.044uA
57	479mV	50.1V	6.610uA	479mV	50.1V	7.611uA
58	480mV	49.8V	9.814uA	480mV	52.3V	8.415uA
59	476mV	50.0V	8.484uA	480mV	51.8V	8.030uA
60	477mV	51.1V	6.851uA	478mV	51.4V	7.023uA
61	478mV	51.3V	8.303uA	480mV	51.2V	6.556uA
62	478mV	50.4V	6.201uA	480mV	49.9V	9.198uA
63	477mV	51.8V	8.782uA	480mV	52.9V	7.681uA
64	476mV	49.9V	8.216uA	478mV	52.4V	6.631uA
65	477mV	51.0V	8.388uA	476mV	53.4V	7.686uA
66	478mV	51.0V	6.671uA	480mV	50.2V	5.709uA
67	478mV	53.2V	9.758uA	476mV	50.4V	5.824uA
68	480mV	51.4V	6.024uA	481mV	53.0V	8.344uA



# SeCoS Corporation

## High Temperature Storage Life Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 150°C, T=1000hrs

Test Date: 2018.07.04 ~ 2018.08.15

Test Standard : JESD22 STANDER Method-A103

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	478mV	50.1V	6.970uA	479mV	51.0V	6.787uA
70	479mV	52.7V	7.721uA	477mV	52.5V	6.195uA
71	476mV	53.0V	7.723uA	477mV	50.0V	9.626uA
72	479mV	52.7V	9.781uA	479mV	53.6V	6.985uA
73	479mV	53.0V	9.382uA	479mV	52.3V	8.697uA
74	479mV	50.7V	9.815uA	479mV	51.9V	8.106uA
75	481mV	50.5V	9.757uA	477mV	49.8V	8.161uA
76	480mV	51.5V	9.315uA	480mV	50.1V	8.574uA
77	480mV	51.5V	9.315uA	480mV	50.1V	8.574uA

Made By: King Huang

Approval: Peter Yang



# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 121°C , 29.7PSIG, 168Hrs

Test Date: 2018.07.10 ~ 2018.07.18

Test Standard : JESD22 STANDER Method-A102

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	477mV	51.1V	8.195uA	476mV	52.5V	9.642uA
2	477mV	50.0V	7.282uA	479mV	50.5V	6.342uA
3	478mV	51.2V	7.351uA	477mV	52.5V	9.199uA
4	477mV	49.8V	9.320uA	476mV	53.3V	9.493uA
5	479mV	53.6V	8.391uA	479mV	50.5V	6.538uA
6	477mV	53.6V	7.197uA	476mV	52.7V	8.278uA
7	480mV	49.9V	8.088uA	480mV	50.9V	7.790uA
8	478mV	51.9V	6.095uA	480mV	50.7V	6.832uA
9	478mV	51.5V	7.187uA	479mV	51.9V	6.393uA
10	479mV	51.8V	5.939uA	480mV	50.2V	5.953uA
11	478mV	50.2V	5.648uA	479mV	50.5V	5.990uA
12	477mV	53.3V	7.360uA	479mV	50.4V	5.900uA
13	478mV	49.8V	9.376uA	478mV	50.3V	6.966uA
14	480mV	51.2V	7.066uA	476mV	50.3V	7.461uA
15	476mV	50.6V	7.859uA	479mV	52.9V	8.731uA
16	476mV	52.3V	7.963uA	477mV	50.4V	9.479uA
17	477mV	50.6V	5.907uA	478mV	52.6V	5.874uA
18	476mV	50.4V	7.632uA	479mV	51.4V	6.677uA
19	477mV	51.6V	8.983uA	480mV	52.7V	7.387uA
20	479mV	52.1V	5.842uA	478mV	51.1V	9.164uA
21	476mV	52.5V	8.381uA	478mV	52.9V	7.040uA
22	478mV	50.0V	8.269uA	477mV	51.0V	7.653uA
23	480mV	50.2V	7.745uA	476mV	51.5V	7.729uA
24	477mV	53.3V	9.818uA	477mV	51.5V	7.083uA
25	480mV	51.4V	9.832uA	479mV	53.3V	7.702uA
26	476mV	51.8V	7.397uA	478mV	50.5V	7.586uA
27	480mV	52.3V	7.948uA	477mV	51.8V	7.404uA
28	480mV	53.7V	7.796uA	479mV	51.1V	8.463uA
29	476mV	53.3V	8.329uA	478mV	51.8V	9.595uA
30	479mV	50.3V	8.831uA	479mV	50.2V	7.386uA
31	479mV	53.2V	8.015uA	480mV	52.8V	9.850uA
32	479mV	50.2V	7.478uA	480mV	51.4V	8.104uA
33	478mV	51.8V	6.673uA	478mV	51.3V	8.290uA
34	477mV	51.6V	9.356uA	478mV	50.3V	6.683uA





# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 121°C , 29.7PSIG, 168Hrs

Test Date: 2018.07.10 ~ 2018.07.18

Test Standard : JESD22 STANDER Method-A102

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	477mV	49.8V	9.157uA	479mV	53.1V	8.375uA
36	477mV	51.2V	6.275uA	480mV	52.0V	9.738uA
37	478mV	51.0V	8.806uA	479mV	53.6V	7.191uA
38	480mV	52.8V	9.347uA	480mV	52.6V	9.171uA
39	476mV	50.9V	6.953uA	479mV	50.5V	9.215uA
40	480mV	53.6V	6.725uA	479mV	53.0V	6.105uA
41	479mV	53.2V	9.217uA	478mV	53.1V	7.228uA
42	477mV	51.8V	7.218uA	478mV	50.5V	9.027uA
43	480mV	52.9V	6.138uA	479mV	51.6V	7.143uA
44	480mV	52.1V	8.559uA	481mV	53.6V	6.632uA
45	477mV	53.4V	6.896uA	479mV	50.2V	9.452uA
46	478mV	51.3V	8.096uA	479mV	50.1V	5.640uA
47	478mV	51.0V	9.163uA	478mV	51.3V	8.481uA
48	478mV	49.8V	6.928uA	477mV	51.6V	6.751uA
49	478mV	50.0V	6.572uA	476mV	50.0V	7.053uA
50	479mV	52.0V	8.563uA	480mV	50.8V	6.886uA
51	478mV	49.8V	7.287uA	480mV	51.6V	7.538uA
52	478mV	52.8V	8.812uA	479mV	49.9V	7.458uA
53	480mV	51.6V	8.632uA	479mV	52.1V	5.832uA
54	479mV	53.2V	8.733uA	480mV	53.5V	8.910uA
55	480mV	52.5V	8.851uA	477mV	50.8V	9.630uA
56	478mV	53.1V	9.353uA	476mV	50.2V	7.609uA
57	477mV	50.0V	7.638uA	476mV	51.2V	9.512uA
58	476mV	53.1V	8.910uA	479mV	52.8V	9.684uA
59	479mV	52.7V	6.767uA	476mV	53.7V	7.887uA
60	478mV	52.6V	9.582uA	480mV	52.6V	7.411uA
61	477mV	51.1V	7.311uA	481mV	50.9V	5.731uA
62	478mV	49.8V	6.365uA	480mV	52.0V	8.320uA
63	479mV	51.3V	6.071uA	480mV	52.4V	7.624uA
64	480mV	51.5V	9.031uA	478mV	50.2V	7.356uA
65	476mV	51.3V	6.490uA	478mV	52.5V	7.919uA
66	480mV	50.1V	9.773uA	477mV	52.7V	8.519uA
67	479mV	50.0V	7.148uA	480mV	51.2V	7.195uA
68	476mV	51.7V	8.935uA	477mV	49.7V	7.406uA



# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 121°C, 29.7PSIG, 168Hrs

Test Date: 2018.07.10 ~ 2018.07.18

Test Standard : JESD22 STANDER Method-A102

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	476mV	50.1V	9.156uA	476mV	52.7V	8.819uA
70	479mV	52.0V	9.393uA	479mV	51.5V	6.146uA
71	479mV	52.8V	9.595uA	477mV	52.2V	6.855uA
72	478mV	52.1V	7.978uA	479mV	50.3V	5.891uA
73	478mV	52.1V	5.972uA	477mV	52.5V	7.259uA
74	478mV	52.2V	6.702uA	479mV	52.7V	8.850uA
75	477mV	53.4V	6.724uA	478mV	53.3V	9.816uA
76	479mV	53.5V	6.228uA	480mV	51.6V	8.063uA
77	478mV	51.9V	8.613uA	480mV	51.7V	7.783uA

Made By: King Huang

Approval: Peter Yang



# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: -55°C/30min, 150°C/30min, for 1000 Cycle

Test Date: 2018.07.04 ~ 2018.08.28

Test Standard : JESD22 STANDER Method-A104

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	478mV	49.8V	9.668uA	478mV	51.1V	6.841uA
2	480mV	50.5V	9.004uA	477mV	50.3V	9.717uA
3	477mV	50.0V	8.604uA	481mV	51.5V	9.380uA
4	477mV	52.0V	9.707uA	477mV	50.3V	9.620uA
5	477mV	52.9V	6.129uA	479mV	52.7V	7.238uA
6	479mV	51.1V	7.064uA	480mV	52.1V	7.678uA
7	480mV	50.4V	7.149uA	480mV	50.1V	6.884uA
8	478mV	51.2V	5.922uA	476mV	52.8V	8.213uA
9	478mV	51.4V	8.528uA	479mV	52.3V	8.644uA
10	480mV	49.7V	9.060uA	477mV	50.4V	9.573uA
11	477mV	49.8V	6.297uA	476mV	51.8V	8.865uA
12	476mV	50.4V	7.325uA	478mV	52.5V	7.120uA
13	477mV	49.8V	8.214uA	477mV	50.6V	6.995uA
14	476mV	51.5V	9.055uA	479mV	50.1V	9.089uA
15	480mV	52.6V	8.872uA	478mV	53.1V	6.634uA
16	476mV	53.1V	8.169uA	479mV	49.8V	9.228uA
17	478mV	50.7V	6.802uA	477mV	49.8V	8.777uA
18	476mV	50.2V	9.803uA	477mV	51.4V	8.967uA
19	480mV	51.8V	5.839uA	478mV	51.8V	8.623uA
20	477mV	52.3V	7.830uA	478mV	53.6V	8.774uA
21	481mV	53.4V	9.220uA	477mV	52.7V	6.211uA
22	478mV	52.9V	6.336uA	479mV	51.3V	6.347uA
23	476mV	51.0V	9.617uA	480mV	51.9V	9.739uA
24	477mV	53.6V	7.350uA	478mV	52.4V	7.689uA
25	479mV	50.6V	7.372uA	476mV	50.5V	6.311uA
26	479mV	51.2V	7.622uA	476mV	52.4V	6.007uA
27	480mV	50.9V	8.167uA	477mV	53.1V	7.227uA
28	477mV	51.0V	6.800uA	481mV	52.6V	9.096uA
29	480mV	53.0V	6.240uA	479mV	51.4V	5.760uA
30	477mV	51.8V	6.036uA	476mV	49.9V	8.124uA
31	478mV	49.8V	9.178uA	478mV	52.3V	9.048uA
32	476mV	53.2V	8.792uA	478mV	52.6V	9.521uA
33	481mV	53.5V	8.134uA	476mV	49.8V	6.903uA
34	478mV	53.3V	9.570uA	479mV	51.0V	8.967uA



# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: -55°C/30min, 150°C/30min, for 1000 Cycle

Test Date: 2018.07.04 ~ 2018.08.28

Test Standard : JESD22 STANDER Method-A104

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	478mV	53.7V	6.867uA	478mV	53.6V	8.981uA
36	477mV	51.7V	8.779uA	477mV	53.0V	9.391uA
37	476mV	50.7V	9.646uA	480mV	49.9V	6.698uA
38	477mV	51.9V	7.452uA	479mV	51.1V	7.606uA
39	477mV	53.6V	6.359uA	480mV	50.8V	9.446uA
40	478mV	50.2V	9.186uA	480mV	49.7V	6.782uA
41	478mV	50.8V	6.696uA	476mV	52.0V	8.065uA
42	476mV	53.0V	9.153uA	479mV	51.9V	5.616uA
43	479mV	50.1V	8.892uA	480mV	53.7V	7.170uA
44	478mV	50.9V	6.545uA	479mV	52.9V	9.639uA
45	477mV	50.1V	6.821uA	476mV	51.8V	9.757uA
46	479mV	51.8V	7.235uA	480mV	51.4V	5.791uA
47	479mV	52.9V	7.015uA	477mV	49.9V	7.541uA
48	476mV	52.8V	5.898uA	478mV	50.2V	7.135uA
49	477mV	51.9V	7.469uA	478mV	53.4V	9.606uA
50	479mV	50.4V	7.634uA	477mV	51.0V	6.826uA
51	479mV	51.5V	6.539uA	476mV	51.0V	6.546uA
52	476mV	50.9V	9.421uA	476mV	50.2V	8.818uA
53	481mV	50.9V	5.816uA	480mV	53.2V	6.423uA
54	479mV	51.9V	5.971uA	479mV	51.9V	5.840uA
55	480mV	53.6V	8.069uA	480mV	53.3V	8.078uA
56	476mV	50.7V	6.520uA	477mV	53.2V	8.400uA
57	477mV	50.9V	9.597uA	480mV	50.7V	7.116uA
58	477mV	50.8V	9.234uA	478mV	51.1V	8.491uA
59	476mV	53.3V	9.478uA	480mV	50.8V	8.577uA
60	478mV	51.2V	7.711uA	477mV	52.0V	6.547uA
61	476mV	51.1V	9.244uA	477mV	51.7V	6.597uA
62	478mV	51.7V	8.401uA	477mV	52.8V	7.376uA
63	479mV	49.9V	9.803uA	480mV	51.5V	6.753uA
64	478mV	51.2V	7.018uA	478mV	52.7V	5.729uA
65	480mV	51.0V	9.880uA	480mV	49.9V	5.627uA
66	477mV	50.1V	8.149uA	479mV	50.5V	7.865uA
67	479mV	51.6V	7.239uA	476mV	52.0V	9.898uA
68	476mV	50.2V	9.608uA	476mV	51.6V	6.809uA





# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: -55°C/30min, 150°C/30min, for 1000 Cycle

Test Date: 2018.07.04 ~ 2018.08.28

Test Standard : JESD22 STANDER Method-A104

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	477mV	50.9V	7.976uA	480mV	49.9V	8.546uA
70	480mV	52.4V	9.137uA	478mV	50.8V	6.238uA
71	479mV	52.3V	8.035uA	481mV	53.2V	6.870uA
72	479mV	52.2V	8.041uA	479mV	50.4V	5.760uA
73	477mV	50.3V	8.950uA	477mV	50.2V	7.512uA
74	476mV	49.9V	5.890uA	478mV	51.7V	6.367uA
75	479mV	53.2V	7.453uA	476mV	52.7V	8.306uA
76	476mV	50.9V	6.964uA	478mV	51.9V	6.032uA
77	477mV	51.2V	7.408uA	476mV	53.2V	7.078uA

Made By: King Huang

Approval: Peter Yang



## High Temperature High Humidity Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 85±2°C , 85±5%RH, 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	477mV	49.8V	7.970uA	478mV	51.9V	6.539uA
2	476mV	50.9V	8.273uA	478mV	52.5V	7.833uA
3	478mV	52.5V	5.885uA	481mV	50.9V	9.297uA
4	476mV	50.1V	9.767uA	478mV	53.6V	9.644uA
5	476mV	52.9V	6.890uA	477mV	53.3V	7.007uA
6	477mV	52.9V	8.396uA	479mV	52.9V	9.893uA
7	479mV	52.8V	6.852uA	478mV	53.5V	5.607uA
8	478mV	49.8V	5.738uA	479mV	51.0V	7.621uA
9	479mV	49.7V	9.896uA	479mV	51.6V	6.081uA
10	480mV	52.7V	6.734uA	481mV	52.0V	8.743uA
11	476mV	52.9V	5.884uA	478mV	50.3V	5.721uA
12	480mV	49.9V	8.344uA	478mV	51.1V	8.283uA
13	479mV	53.4V	6.384uA	479mV	50.4V	8.563uA
14	479mV	51.1V	7.163uA	476mV	53.4V	8.931uA
15	479mV	52.5V	5.690uA	480mV	53.4V	7.602uA
16	480mV	53.0V	8.385uA	477mV	52.7V	9.349uA
17	476mV	50.4V	7.895uA	481mV	52.0V	5.838uA
18	478mV	51.4V	6.620uA	480mV	52.3V	5.663uA
19	477mV	52.1V	9.003uA	478mV	52.2V	8.824uA
20	479mV	51.3V	7.689uA	480mV	52.6V	6.392uA
21	478mV	50.0V	8.610uA	477mV	53.1V	7.709uA
22	480mV	50.2V	7.648uA	476mV	53.5V	5.719uA
23	478mV	52.4V	5.705uA	476mV	53.1V	7.498uA
24	477mV	50.3V	7.800uA	477mV	51.4V	5.831uA
25	477mV	52.9V	8.760uA	477mV	50.5V	7.867uA
26	477mV	53.5V	6.636uA	480mV	51.5V	7.203uA
27	480mV	53.4V	9.858uA	480mV	51.2V	7.979uA
28	476mV	52.5V	7.871uA	480mV	52.1V	9.225uA
29	478mV	51.2V	9.861uA	479mV	53.7V	8.015uA
30	478mV	53.2V	7.115uA	478mV	53.1V	9.222uA
31	480mV	53.1V	7.420uA	477mV	53.3V	7.049uA
32	478mV	50.0V	9.119uA	476mV	50.9V	9.506uA
33	477mV	53.3V	9.318uA	478mV	52.9V	8.528uA
34	476mV	53.5V	9.619uA	480mV	50.7V	9.094uA



## High Temperature High Humidity Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 85±2°C , 85±5%RH, 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	480mV	51.2V	9.757uA	479mV	49.7V	5.808uA
36	478mV	50.4V	6.991uA	476mV	51.5V	6.253uA
37	479mV	53.6V	6.112uA	477mV	50.2V	8.686uA
38	478mV	53.1V	8.850uA	480mV	51.3V	7.718uA
39	476mV	51.8V	9.136uA	476mV	50.7V	8.816uA
40	480mV	53.7V	9.347uA	479mV	50.4V	8.079uA
41	480mV	51.0V	6.545uA	478mV	53.7V	8.293uA
42	476mV	51.6V	7.989uA	481mV	49.8V	9.220uA
43	479mV	51.8V	8.224uA	479mV	51.7V	6.261uA
44	479mV	52.6V	5.619uA	480mV	51.6V	8.686uA
45	478mV	49.9V	6.820uA	476mV	50.8V	8.184uA
46	477mV	52.1V	6.402uA	481mV	51.3V	5.627uA
47	480mV	50.7V	6.446uA	479mV	52.3V	9.156uA
48	476mV	50.1V	6.367uA	477mV	53.6V	7.453uA
49	477mV	50.3V	9.765uA	477mV	53.3V	9.555uA
50	479mV	53.4V	8.268uA	478mV	53.2V	5.846uA
51	479mV	49.8V	7.411uA	480mV	52.4V	8.338uA
52	478mV	50.5V	7.006uA	477mV	50.5V	8.412uA
53	476mV	53.2V	9.294uA	479mV	51.6V	7.581uA
54	477mV	52.0V	7.187uA	479mV	50.1V	7.356uA
55	478mV	50.6V	9.047uA	476mV	53.5V	7.538uA
56	479mV	51.3V	8.584uA	478mV	52.3V	7.184uA
57	480mV	51.9V	6.340uA	480mV	53.2V	6.290uA
58	480mV	53.2V	8.221uA	478mV	52.5V	8.632uA
59	479mV	50.5V	7.772uA	477mV	52.5V	7.898uA
60	479mV	51.4V	6.120uA	479mV	52.7V	8.587uA
61	476mV	51.4V	9.538uA	480mV	49.8V	9.715uA
62	477mV	52.1V	6.727uA	476mV	50.0V	5.895uA
63	478mV	52.5V	8.451uA	479mV	50.7V	6.111uA
64	477mV	53.3V	8.119uA	477mV	50.0V	7.580uA
65	478mV	50.8V	5.948uA	478mV	51.3V	7.561uA
66	477mV	52.3V	7.418uA	479mV	51.6V	6.522uA
67	479mV	53.4V	8.398uA	480mV	52.9V	8.296uA
68	477mV	51.8V	6.022uA	478mV	49.9V	6.689uA



# SeCoS Corporation

## High Temperature High Humidity Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 85±2°C , 85±5%RH, 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	480mV	52.9V	7.212uA	479mV	51.2V	7.606uA
70	478mV	52.1V	6.974uA	478mV	53.5V	6.996uA
71	480mV	49.7V	5.755uA	480mV	51.0V	7.602uA
72	477mV	50.5V	7.530uA	479mV	52.3V	7.121uA
73	477mV	51.7V	6.893uA	480mV	50.7V	5.764uA
74	477mV	50.6V	8.415uA	477mV	53.4V	5.917uA
75	476mV	52.9V	6.562uA	477mV	51.4V	7.945uA
76	478mV	53.1V	8.905uA	479mV	50.7V	7.476uA
77	481mV	51.8V	6.663uA	477mV	51.9V	9.832uA

Made By: King Huang

Approval: Peter Yang



## High Temperature High Humidity Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 85±2°C , 85±5%RH, 80% VR 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	478mV	50.3V	8.484uA	477mV	52.9V	9.659uA
2	477mV	51.9V	5.885uA	478mV	50.5V	8.047uA
3	477mV	52.3V	7.841uA	479mV	51.1V	6.162uA
4	479mV	53.5V	8.797uA	480mV	50.0V	6.581uA
5	477mV	51.5V	8.727uA	479mV	52.5V	9.348uA
6	477mV	50.1V	7.575uA	476mV	52.9V	7.160uA
7	478mV	52.4V	5.897uA	476mV	50.4V	8.432uA
8	477mV	52.5V	6.598uA	478mV	50.6V	9.662uA
9	477mV	49.9V	9.478uA	480mV	53.4V	7.417uA
10	480mV	53.3V	7.817uA	477mV	50.9V	9.757uA
11	478mV	49.7V	8.775uA	478mV	50.5V	7.389uA
12	477mV	52.7V	9.632uA	476mV	53.4V	6.766uA
13	478mV	49.9V	8.947uA	481mV	51.2V	8.191uA
14	476mV	49.9V	9.895uA	478mV	52.4V	9.304uA
15	478mV	51.7V	9.526uA	477mV	50.4V	5.700uA
16	478mV	51.5V	6.567uA	477mV	51.0V	8.928uA
17	479mV	52.0V	8.115uA	476mV	50.9V	9.212uA
18	478mV	52.2V	7.124uA	481mV	51.3V	7.893uA
19	480mV	52.8V	6.305uA	476mV	52.3V	9.357uA
20	479mV	49.8V	7.185uA	478mV	52.0V	9.393uA
21	477mV	49.8V	8.846uA	477mV	51.1V	6.558uA
22	476mV	51.0V	9.884uA	478mV	49.9V	8.216uA
23	478mV	51.6V	8.678uA	479mV	50.3V	6.046uA
24	480mV	50.8V	7.361uA	479mV	52.0V	6.655uA
25	479mV	50.1V	8.558uA	480mV	53.7V	8.434uA
26	478mV	53.4V	5.822uA	480mV	52.0V	9.816uA
27	478mV	50.9V	7.712uA	479mV	51.0V	6.680uA
28	478mV	50.7V	6.228uA	480mV	52.7V	6.714uA
29	477mV	50.6V	6.074uA	477mV	53.0V	6.849uA
30	480mV	51.5V	8.704uA	480mV	52.4V	9.607uA
31	477mV	51.3V	6.057uA	481mV	52.9V	6.373uA
32	477mV	50.3V	8.486uA	481mV	51.2V	9.175uA
33	479mV	51.6V	8.975uA	479mV	51.5V	9.635uA
34	481mV	53.3V	9.748uA	478mV	53.2V	6.148uA



## High Temperature High Humidity Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 85±2°C , 85±5%RH, 80% VR 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	476mV	51.3V	6.334uA	478mV	50.2V	8.909uA
36	479mV	53.2V	7.956uA	477mV	50.0V	5.890uA
37	480mV	52.3V	5.891uA	477mV	50.7V	7.864uA
38	480mV	50.2V	7.100uA	478mV	53.5V	6.303uA
39	479mV	53.3V	9.698uA	479mV	52.3V	6.307uA
40	478mV	51.8V	8.504uA	481mV	53.4V	9.198uA
41	481mV	50.4V	6.242uA	479mV	50.1V	8.112uA
42	480mV	50.6V	5.833uA	476mV	51.8V	8.436uA
43	478mV	52.2V	7.999uA	478mV	50.2V	7.491uA
44	478mV	51.1V	7.330uA	481mV	52.7V	5.954uA
45	479mV	49.9V	6.692uA	479mV	52.7V	6.834uA
46	481mV	51.7V	9.787uA	476mV	49.9V	7.801uA
47	478mV	53.3V	6.924uA	481mV	53.0V	8.104uA
48	480mV	52.5V	8.625uA	477mV	53.3V	6.992uA
49	478mV	51.8V	8.259uA	478mV	50.1V	7.169uA
50	478mV	50.0V	9.661uA	476mV	53.2V	8.856uA
51	477mV	50.4V	8.140uA	480mV	50.6V	9.567uA
52	477mV	52.5V	7.221uA	478mV	49.7V	8.357uA
53	480mV	52.4V	8.542uA	476mV	53.1V	6.952uA
54	480mV	52.4V	9.627uA	478mV	51.1V	5.851uA
55	477mV	51.3V	8.098uA	476mV	50.5V	7.117uA
56	481mV	51.0V	9.040uA	480mV	51.2V	6.234uA
57	479mV	51.0V	8.659uA	479mV	49.9V	8.782uA
58	477mV	50.8V	8.419uA	480mV	50.6V	5.759uA
59	476mV	51.0V	7.520uA	477mV	51.2V	6.406uA
60	479mV	53.1V	7.480uA	478mV	51.7V	8.419uA
61	478mV	50.6V	9.723uA	480mV	51.7V	8.527uA
62	479mV	51.2V	5.798uA	477mV	52.4V	6.999uA
63	476mV	51.9V	8.473uA	479mV	52.8V	7.020uA
64	478mV	50.7V	9.209uA	477mV	52.1V	7.424uA
65	476mV	51.1V	6.495uA	477mV	53.5V	5.900uA
66	477mV	51.0V	9.746uA	478mV	51.5V	9.294uA
67	478mV	50.8V	8.118uA	477mV	52.7V	9.121uA
68	477mV	53.6V	8.426uA	476mV	51.9V	9.639uA





# SeCoS Corporation

## High Temperature High Humidity Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 85±2°C , 85±5%RH, 80% VR 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	477mV	49.7V	8.902uA	477mV	52.0V	8.414uA
70	480mV	50.5V	9.416uA	478mV	50.8V	5.815uA
71	480mV	52.2V	8.939uA	480mV	50.8V	5.896uA
72	479mV	53.4V	7.981uA	479mV	52.5V	5.863uA
73	480mV	52.2V	6.791uA	478mV	50.6V	7.592uA
74	480mV	53.5V	6.055uA	477mV	50.2V	8.174uA
75	477mV	51.3V	6.122uA	477mV	51.5V	8.796uA
76	476mV	53.3V	9.268uA	478mV	51.4V	9.026uA
77	480mV	53.0V	9.482uA	478mV	50.1V	6.422uA

Made By: King Huang

Approval: Peter Yang



# SeCoS Corporation

## Solderability Test Data

Report No : T180702-340A

Part No : SM340A-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<520mV@IF=3A ; VBR>40V@I1=1mA

IR<200uA@VR=40V

Test Condition: 245 ± 5°C, 5Sec

Test Date: 2018.08.27

Test Standard : JESD22 STANDER Method-B102

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	481mV	51.7V	6.606uA	479mV	53.5V	6.685uA
2	479mV	50.8V	7.609uA	480mV	50.1V	8.986uA
3	476mV	53.3V	7.606uA	480mV	51.3V	8.079uA
4	476mV	52.2V	6.643uA	479mV	52.2V	8.142uA
5	477mV	52.3V	7.698uA	478mV	50.8V	9.342uA
6	480mV	50.8V	9.231uA	476mV	50.1V	6.360uA
7	480mV	52.2V	5.744uA	478mV	53.1V	5.986uA
8	477mV	51.3V	6.019uA	478mV	51.9V	6.051uA
9	478mV	51.2V	8.203uA	480mV	51.9V	9.558uA
10	479mV	52.0V	7.176uA	476mV	51.1V	8.788uA

Made By: King Huang

Approval: Peter Yang



## Reliability Testing Summary Report

Date: 2018/08/31

Document No.: SL18-07-5100B

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SM5100B-C	100±5°C, 80% VR, T=1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SM5100B-C	150°C, T=1000hrs		77	0	0	ACC
PCT Pressure Cooker Test	SM5100B-C	121°C, 29.7PSIG, 168hrs		77	0	0	ACC
TCT Temperature Cycle Test	SM5100B-C	-55°C/30min, 150°C/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SM5100B-C	85 ± 2°C, RH=85±5%, 1000hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SM5100B-C	85 ± 2°C, RH=85±5%, 80% VR, 1000hrs		77	0	0	ACC
Solderability	SM5100B-C	245 ± 5°C, 5Sec the inspected area of each lead must have 95% solder coverage minimum		10	0	0	ACC

**Judgment:**

qualified     unqualified

Testing Start Date: 2018.07.01    Testing End Date: 2018.08.31

Tester: King Huang    Approval: Peter Yang



## Electrical Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 25°C

Test Date: 2018.07.02

Test Standard : Specifications

Operator: Joe Lee

Test Result: PASS

No	VF (mV)	VBR (V)	IR (uA)
1	748mV	120.9V	0.020uA
2	749mV	119.2V	0.272uA
3	742mV	116.9V	0.219uA
4	753mV	118.3V	0.228uA
5	741mV	117.9V	0.183uA
6	745mV	118.0V	0.185uA
7	745mV	119.6V	0.230uA
8	750mV	119.9V	0.233uA
9	753mV	116.8V	0.248uA
10	754mV	117.6V	0.174uA
11	746mV	118.7V	0.241uA
12	753mV	117.8V	0.262uA
13	742mV	120.8V	0.195uA
14	750mV	115.3V	0.189uA
15	751mV	119.8V	0.241uA
16	747mV	120.8V	0.257uA
17	744mV	121.0V	0.198uA
18	746mV	118.1V	0.264uA
19	740mV	117.5V	0.209uA
20	748mV	117.8V	0.235uA
21	746mV	119.6V	0.239uA
22	745mV	115.9V	0.181uA
23	743mV	118.7V	0.173uA
24	749mV	118.2V	0.245uA
25	746mV	117.5V	0.207uA
26	752mV	117.0V	0.219uA
27	740mV	118.1V	0.206uA
28	754mV	116.6V	0.158uA
29	744mV	117.1V	0.168uA
30	746mV	115.1V	0.278uA
31	751mV	120.6V	0.268uA
32	751mV	120.8V	0.222uA
33	740mV	118.7V	0.188uA
34	753mV	118.3V	0.260uA
35	751mV	115.6V	0.189uA



## Electrical Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 25°C

Test Date: 2018.07.02

Test Standard : Specifications

Operator: Joe Lee

Test Result: PASS

No	VF (mV)	VBR (V)	IR (uA)
36	749mV	120.0V	0.169uA
37	742mV	120.0V	0.267uA
38	754mV	119.0V	0.248uA
39	753mV	120.8V	0.172uA
40	752mV	118.2V	0.158uA
41	754mV	120.6V	0.282uA
42	745mV	119.8V	0.151uA
43	751mV	116.5V	0.195uA
44	742mV	116.5V	0.221uA
45	749mV	118.2V	0.172uA
46	744mV	116.0V	0.268uA
47	745mV	119.3V	0.268uA
48	749mV	117.4V	0.160uA
49	748mV	119.3V	0.167uA
50	747mV	118.5V	0.187uA
51	750mV	116.9V	0.201uA
52	742mV	116.7V	0.242uA
53	746mV	115.9V	0.269uA
54	741mV	118.1V	0.178uA
55	744mV	115.7V	0.160uA
56	755mV	115.2V	0.183uA
57	748mV	117.9V	0.249uA
58	743mV	116.2V	0.231uA
59	746mV	116.5V	0.278uA
60	748mV	115.1V	0.170uA
61	748mV	115.3V	0.151uA
62	751mV	118.4V	0.268uA
63	752mV	119.9V	0.186uA
64	755mV	118.8V	0.208uA
65	744mV	115.2V	0.165uA
66	752mV	118.1V	0.237uA
67	747mV	116.2V	0.272uA
68	747mV	118.2V	0.204uA
69	750mV	119.2V	0.261uA
70	750mV	117.9V	0.208uA



# SeCoS Corporation

## Electrical Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 25°C

Test Date: 2018.07.02

Test Standard : Specifications

Operator: Joe Lee

Test Result: PASS

No	VF (mV)	VBR (V)	IR (uA)
71	752mV	119.8V	0.199uA
72	741mV	119.0V	0.188uA
73	746mV	116.0V	0.254uA
74	742mV	117.3V	0.207uA
75	753mV	120.8V	0.220uA
76	745mV	115.6V	0.168uA
77	742mV	116.8V	0.216uA

Made By: King Huang

Approval: Peter Yang





## High Temperature Reverse Bias Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 100±5°C , 80% VR, T=1000hrs

Test Date: 2018.07.03 ~ 2018.08.14

Test Standard : JESD22 STANDER Method-A108

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	745mV	117.2V	0.017uA	743mV	117.6V	0.021uA
2	742mV	118.9V	0.252uA	742mV	118.1V	0.270uA
3	754mV	119.5V	0.228uA	754mV	119.2V	0.153uA
4	750mV	120.4V	0.231uA	755mV	115.5V	0.164uA
5	754mV	119.3V	0.205uA	753mV	117.6V	0.238uA
6	742mV	120.8V	0.265uA	755mV	119.0V	0.181uA
7	746mV	117.6V	0.257uA	742mV	116.6V	0.251uA
8	750mV	120.5V	0.161uA	745mV	118.8V	0.199uA
9	746mV	118.6V	0.208uA	752mV	118.0V	0.154uA
10	749mV	117.0V	0.250uA	740mV	120.5V	0.224uA
11	746mV	120.5V	0.258uA	754mV	117.8V	0.180uA
12	748mV	118.4V	0.163uA	741mV	116.4V	0.288uA
13	754mV	115.7V	0.170uA	752mV	119.4V	0.245uA
14	746mV	119.4V	0.173uA	741mV	119.1V	0.195uA
15	755mV	115.6V	0.154uA	750mV	116.5V	0.264uA
16	743mV	119.1V	0.234uA	752mV	118.5V	0.222uA
17	746mV	117.0V	0.176uA	744mV	116.9V	0.259uA
18	753mV	120.0V	0.171uA	749mV	115.3V	0.267uA
19	746mV	116.4V	0.171uA	749mV	116.1V	0.216uA
20	754mV	117.6V	0.260uA	743mV	119.1V	0.191uA
21	741mV	119.5V	0.178uA	755mV	117.4V	0.260uA
22	741mV	117.6V	0.164uA	754mV	120.2V	0.152uA
23	748mV	118.8V	0.183uA	743mV	119.4V	0.266uA
24	743mV	120.7V	0.271uA	743mV	118.0V	0.215uA
25	742mV	115.5V	0.267uA	749mV	120.2V	0.275uA
26	752mV	118.1V	0.228uA	744mV	121.0V	0.169uA
27	741mV	119.3V	0.171uA	746mV	118.9V	0.194uA
28	741mV	116.6V	0.272uA	753mV	116.2V	0.197uA
29	740mV	117.7V	0.236uA	743mV	117.9V	0.229uA
30	754mV	116.3V	0.187uA	744mV	117.3V	0.268uA
31	754mV	115.4V	0.220uA	754mV	117.0V	0.206uA
32	752mV	116.7V	0.195uA	744mV	116.4V	0.251uA
33	755mV	115.1V	0.205uA	754mV	118.9V	0.260uA
34	745mV	118.9V	0.204uA	741mV	120.2V	0.164uA



## High Temperature Reverse Bias Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 100±5°C , 80% VR, T=1000hrs

Test Date: 2018.07.03 ~ 2018.08.14

Test Standard : JESD22 STANDER Method-A108

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	742mV	116.3V	0.191uA	751mV	119.2V	0.180uA
36	744mV	120.5V	0.206uA	745mV	120.7V	0.212uA
37	755mV	118.6V	0.278uA	742mV	120.9V	0.209uA
38	742mV	119.6V	0.184uA	744mV	115.4V	0.150uA
39	741mV	116.8V	0.231uA	752mV	117.4V	0.271uA
40	751mV	117.0V	0.234uA	748mV	117.3V	0.187uA
41	747mV	115.8V	0.222uA	741mV	116.9V	0.166uA
42	740mV	117.3V	0.284uA	749mV	116.4V	0.253uA
43	745mV	116.4V	0.245uA	748mV	115.8V	0.250uA
44	741mV	115.7V	0.189uA	747mV	117.7V	0.194uA
45	751mV	120.4V	0.255uA	748mV	120.7V	0.200uA
46	743mV	115.1V	0.264uA	753mV	117.7V	0.252uA
47	752mV	118.0V	0.223uA	743mV	120.1V	0.225uA
48	741mV	117.2V	0.194uA	748mV	120.2V	0.150uA
49	755mV	117.4V	0.274uA	741mV	118.1V	0.267uA
50	751mV	115.4V	0.237uA	752mV	119.9V	0.218uA
51	746mV	119.2V	0.229uA	749mV	118.9V	0.201uA
52	742mV	118.9V	0.190uA	751mV	116.0V	0.227uA
53	744mV	118.4V	0.204uA	742mV	120.5V	0.284uA
54	744mV	120.0V	0.178uA	750mV	115.5V	0.240uA
55	750mV	118.6V	0.278uA	753mV	118.3V	0.202uA
56	750mV	117.3V	0.270uA	741mV	118.0V	0.193uA
57	754mV	120.0V	0.157uA	746mV	120.1V	0.251uA
58	750mV	115.8V	0.153uA	748mV	120.7V	0.190uA
59	747mV	115.9V	0.255uA	744mV	118.0V	0.182uA
60	741mV	120.2V	0.177uA	752mV	117.2V	0.228uA
61	744mV	115.3V	0.170uA	749mV	117.7V	0.176uA
62	743mV	120.2V	0.242uA	742mV	115.6V	0.189uA
63	748mV	115.9V	0.259uA	744mV	118.6V	0.273uA
64	747mV	119.8V	0.164uA	748mV	118.5V	0.279uA
65	742mV	116.6V	0.194uA	743mV	116.1V	0.176uA
66	750mV	119.8V	0.160uA	748mV	119.9V	0.216uA
67	753mV	117.9V	0.174uA	747mV	118.1V	0.250uA
68	744mV	116.2V	0.168uA	743mV	119.7V	0.184uA



# SeCoS Corporation

## High Temperature Reverse Bias Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 100±5°C , 80% VR, T=1000hrs

Test Date: 2018.07.03 ~ 2018.08.14

Test Standard : JESD22 STANDER Method-A108

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	741mV	119.6V	0.191uA	747mV	120.1V	0.159uA
70	746mV	117.5V	0.274uA	748mV	118.4V	0.181uA
71	745mV	117.4V	0.161uA	754mV	120.8V	0.183uA
72	751mV	119.3V	0.285uA	754mV	115.7V	0.181uA
73	740mV	115.5V	0.196uA	744mV	120.9V	0.272uA
74	744mV	120.5V	0.270uA	749mV	119.7V	0.156uA
75	745mV	117.2V	0.203uA	752mV	119.9V	0.264uA
76	744mV	115.8V	0.265uA	751mV	117.9V	0.166uA
77	753mV	117.1V	0.175uA	750mV	117.1V	0.194uA

Made By: King Huang

Approval: Peter Yang



## High Temperature Storage Life Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 150°C, T=1000hrs

Test Date: 2018.07.04 ~ 2018.08.15

Test Standard : JESD22 STANDER Method-A103

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	746mV	120.5V	0.019uA	750mV	120.9V	0.019uA
2	747mV	116.8V	0.252uA	755mV	117.8V	0.198uA
3	745mV	116.3V	0.282uA	751mV	119.5V	0.240uA
4	741mV	120.6V	0.162uA	755mV	118.5V	0.198uA
5	749mV	119.4V	0.160uA	755mV	119.5V	0.173uA
6	748mV	115.3V	0.154uA	754mV	120.1V	0.271uA
7	741mV	120.5V	0.218uA	746mV	118.3V	0.272uA
8	752mV	118.1V	0.204uA	741mV	117.7V	0.288uA
9	751mV	118.9V	0.253uA	747mV	121.0V	0.286uA
10	755mV	118.8V	0.192uA	741mV	120.4V	0.204uA
11	752mV	118.9V	0.173uA	754mV	116.5V	0.202uA
12	754mV	118.9V	0.202uA	754mV	119.7V	0.239uA
13	750mV	117.0V	0.265uA	746mV	118.4V	0.217uA
14	741mV	116.5V	0.235uA	744mV	118.4V	0.175uA
15	752mV	118.0V	0.236uA	745mV	119.0V	0.195uA
16	748mV	118.0V	0.256uA	746mV	115.7V	0.244uA
17	747mV	115.3V	0.154uA	746mV	121.0V	0.193uA
18	743mV	117.0V	0.255uA	753mV	118.2V	0.282uA
19	746mV	118.9V	0.271uA	749mV	115.3V	0.256uA
20	751mV	120.4V	0.261uA	752mV	119.3V	0.213uA
21	743mV	119.4V	0.240uA	743mV	120.9V	0.281uA
22	751mV	117.0V	0.269uA	750mV	118.7V	0.191uA
23	752mV	117.6V	0.255uA	742mV	120.1V	0.219uA
24	742mV	115.8V	0.153uA	747mV	118.8V	0.197uA
25	742mV	115.8V	0.154uA	750mV	116.5V	0.282uA
26	747mV	120.0V	0.195uA	745mV	121.0V	0.227uA
27	740mV	116.9V	0.253uA	753mV	119.2V	0.180uA
28	741mV	118.3V	0.279uA	745mV	115.1V	0.205uA
29	745mV	120.4V	0.272uA	753mV	115.3V	0.164uA
30	753mV	120.8V	0.279uA	748mV	120.7V	0.150uA
31	742mV	120.9V	0.152uA	747mV	116.1V	0.256uA
32	742mV	116.2V	0.282uA	747mV	119.5V	0.166uA
33	742mV	115.1V	0.257uA	742mV	119.9V	0.181uA
34	750mV	119.1V	0.249uA	745mV	115.9V	0.207uA



## High Temperature Storage Life Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 150°C, T=1000hrs

Test Date: 2018.07.04 ~ 2018.08.15

Test Standard : JESD22 STANDER Method-A103

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	744mV	115.6V	0.272uA	748mV	119.2V	0.222uA
36	747mV	117.3V	0.223uA	748mV	115.7V	0.173uA
37	742mV	119.8V	0.289uA	743mV	116.2V	0.285uA
38	741mV	119.5V	0.192uA	745mV	120.4V	0.163uA
39	749mV	116.0V	0.203uA	755mV	119.6V	0.249uA
40	750mV	119.9V	0.150uA	743mV	118.4V	0.203uA
41	744mV	116.6V	0.286uA	752mV	117.0V	0.240uA
42	742mV	118.0V	0.236uA	754mV	115.1V	0.232uA
43	753mV	116.7V	0.177uA	743mV	121.0V	0.189uA
44	754mV	117.9V	0.260uA	741mV	116.5V	0.156uA
45	754mV	120.3V	0.208uA	754mV	116.0V	0.223uA
46	745mV	116.5V	0.261uA	747mV	118.1V	0.186uA
47	750mV	115.4V	0.158uA	747mV	118.8V	0.216uA
48	748mV	116.8V	0.258uA	752mV	120.3V	0.186uA
49	753mV	118.9V	0.192uA	752mV	117.1V	0.159uA
50	745mV	117.3V	0.159uA	753mV	119.9V	0.227uA
51	744mV	119.7V	0.162uA	741mV	115.1V	0.208uA
52	750mV	119.6V	0.153uA	750mV	116.1V	0.253uA
53	742mV	117.4V	0.195uA	744mV	117.2V	0.202uA
54	749mV	118.6V	0.213uA	744mV	115.9V	0.168uA
55	744mV	120.1V	0.258uA	749mV	116.9V	0.234uA
56	748mV	118.5V	0.224uA	754mV	117.4V	0.169uA
57	753mV	120.9V	0.150uA	741mV	118.8V	0.249uA
58	746mV	115.2V	0.235uA	745mV	119.3V	0.164uA
59	753mV	120.7V	0.175uA	745mV	115.6V	0.251uA
60	744mV	120.4V	0.218uA	751mV	117.9V	0.258uA
61	751mV	117.7V	0.232uA	752mV	116.6V	0.281uA
62	744mV	117.2V	0.254uA	753mV	119.3V	0.258uA
63	748mV	115.8V	0.186uA	750mV	119.7V	0.217uA
64	742mV	115.7V	0.279uA	743mV	120.1V	0.253uA
65	752mV	115.4V	0.278uA	751mV	120.4V	0.223uA
66	755mV	119.1V	0.204uA	754mV	116.4V	0.188uA
67	754mV	115.3V	0.244uA	754mV	116.1V	0.195uA
68	741mV	115.2V	0.260uA	747mV	119.1V	0.258uA



# SeCoS Corporation

## High Temperature Storage Life Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 150°C, T=1000hrs

Test Date: 2018.07.04 ~ 2018.08.15

Test Standard : JESD22 STANDER Method-A103

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	747mV	119.0V	0.214uA	749mV	115.6V	0.181uA
70	747mV	115.0V	0.199uA	750mV	116.0V	0.273uA
71	749mV	116.2V	0.206uA	752mV	120.2V	0.201uA
72	745mV	120.2V	0.158uA	754mV	120.6V	0.201uA
73	744mV	115.6V	0.226uA	751mV	115.4V	0.171uA
74	749mV	118.5V	0.177uA	754mV	117.4V	0.151uA
75	753mV	118.9V	0.245uA	745mV	116.6V	0.155uA
76	754mV	115.9V	0.267uA	755mV	115.2V	0.266uA
77	747mV	119.1V	0.253uA	755mV	117.8V	0.194uA

Made By: King Huang

Approval: Peter Yang





# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 121°C, 29.7PSIG, 168Hrs

Test Date: 2018.07.16 ~ 2018.07.24

Test Standard : JESD22 STANDER Method-A102

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	747mV	115.0V	0.021uA	749mV	116.8V	0.018uA
2	744mV	121.0V	0.204uA	751mV	120.1V	0.162uA
3	752mV	116.8V	0.254uA	747mV	116.8V	0.215uA
4	750mV	118.5V	0.264uA	747mV	119.4V	0.185uA
5	743mV	117.2V	0.153uA	749mV	118.3V	0.232uA
6	745mV	116.7V	0.216uA	751mV	119.0V	0.289uA
7	742mV	116.4V	0.271uA	747mV	115.8V	0.241uA
8	748mV	118.4V	0.289uA	752mV	120.7V	0.281uA
9	754mV	115.3V	0.159uA	751mV	119.3V	0.199uA
10	741mV	115.8V	0.280uA	743mV	118.7V	0.254uA
11	745mV	120.6V	0.252uA	745mV	115.2V	0.165uA
12	750mV	116.9V	0.242uA	750mV	118.2V	0.155uA
13	750mV	120.7V	0.288uA	741mV	116.5V	0.199uA
14	751mV	118.5V	0.288uA	742mV	117.4V	0.160uA
15	746mV	115.2V	0.209uA	749mV	115.1V	0.205uA
16	743mV	115.4V	0.204uA	750mV	118.8V	0.176uA
17	750mV	118.8V	0.220uA	744mV	116.9V	0.192uA
18	740mV	116.6V	0.241uA	741mV	119.9V	0.208uA
19	750mV	116.0V	0.249uA	755mV	120.8V	0.200uA
20	744mV	118.6V	0.163uA	754mV	116.2V	0.207uA
21	741mV	115.5V	0.233uA	752mV	118.2V	0.259uA
22	744mV	117.2V	0.257uA	743mV	115.8V	0.251uA
23	752mV	115.8V	0.279uA	754mV	116.9V	0.178uA
24	743mV	115.4V	0.224uA	745mV	120.8V	0.168uA
25	753mV	118.4V	0.230uA	751mV	120.4V	0.265uA
26	742mV	116.5V	0.243uA	744mV	117.5V	0.212uA
27	746mV	119.7V	0.265uA	746mV	119.2V	0.178uA
28	746mV	119.8V	0.234uA	748mV	119.9V	0.222uA
29	745mV	117.3V	0.228uA	745mV	120.6V	0.221uA
30	740mV	117.4V	0.206uA	740mV	116.9V	0.255uA
31	753mV	119.8V	0.180uA	749mV	117.1V	0.178uA
32	751mV	117.6V	0.153uA	740mV	118.4V	0.279uA
33	751mV	119.1V	0.230uA	746mV	115.2V	0.201uA
34	748mV	120.6V	0.193uA	754mV	117.9V	0.258uA



# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 121°C , 29.7PSIG, 168Hrs

Test Date: 2018.07.16 ~ 2018.07.24

Test Standard : JESD22 STANDER Method-A102

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	746mV	115.3V	0.261uA	749mV	117.0V	0.242uA
36	751mV	115.6V	0.209uA	747mV	118.4V	0.269uA
37	745mV	120.0V	0.171uA	752mV	115.9V	0.258uA
38	754mV	117.4V	0.288uA	741mV	119.0V	0.182uA
39	741mV	115.2V	0.273uA	740mV	116.8V	0.155uA
40	749mV	115.4V	0.172uA	746mV	120.2V	0.155uA
41	749mV	120.8V	0.160uA	743mV	117.2V	0.266uA
42	742mV	117.1V	0.284uA	747mV	116.9V	0.278uA
43	742mV	115.9V	0.211uA	741mV	120.6V	0.260uA
44	745mV	115.3V	0.216uA	745mV	118.9V	0.273uA
45	754mV	117.7V	0.281uA	749mV	119.4V	0.257uA
46	742mV	118.4V	0.240uA	743mV	117.8V	0.269uA
47	741mV	116.2V	0.179uA	745mV	119.0V	0.166uA
48	747mV	120.2V	0.260uA	741mV	119.9V	0.284uA
49	752mV	119.6V	0.261uA	742mV	116.9V	0.189uA
50	740mV	116.3V	0.216uA	754mV	115.8V	0.191uA
51	749mV	115.0V	0.181uA	744mV	119.9V	0.205uA
52	750mV	118.8V	0.176uA	753mV	116.3V	0.227uA
53	746mV	118.6V	0.185uA	741mV	118.4V	0.204uA
54	746mV	120.6V	0.150uA	749mV	120.3V	0.228uA
55	749mV	115.7V	0.175uA	750mV	120.6V	0.229uA
56	748mV	115.2V	0.159uA	745mV	120.2V	0.246uA
57	742mV	118.0V	0.225uA	744mV	118.1V	0.246uA
58	747mV	119.5V	0.261uA	742mV	117.6V	0.285uA
59	741mV	120.2V	0.205uA	746mV	117.6V	0.282uA
60	748mV	118.0V	0.210uA	753mV	116.1V	0.163uA
61	744mV	117.6V	0.214uA	742mV	120.0V	0.273uA
62	748mV	116.3V	0.162uA	744mV	119.6V	0.241uA
63	742mV	119.9V	0.153uA	748mV	117.2V	0.215uA
64	744mV	118.3V	0.206uA	744mV	119.9V	0.217uA
65	743mV	116.8V	0.265uA	753mV	119.6V	0.232uA
66	741mV	115.5V	0.237uA	754mV	120.2V	0.257uA
67	746mV	118.8V	0.272uA	740mV	116.9V	0.190uA
68	752mV	119.7V	0.155uA	742mV	116.4V	0.235uA



# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 121°C, 29.7PSIG, 168Hrs

Test Date: 2018.07.16 ~ 2018.07.24

Test Standard : JESD22 STANDER Method-A102

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	753mV	116.9V	0.264uA	745mV	117.3V	0.175uA
70	741mV	118.8V	0.273uA	746mV	117.4V	0.245uA
71	741mV	119.8V	0.202uA	745mV	118.7V	0.171uA
72	742mV	116.2V	0.279uA	745mV	119.3V	0.195uA
73	749mV	117.0V	0.194uA	749mV	116.9V	0.213uA
74	741mV	120.8V	0.287uA	752mV	116.4V	0.276uA
75	746mV	118.8V	0.191uA	748mV	116.4V	0.221uA
76	744mV	116.5V	0.231uA	745mV	119.7V	0.270uA
77	740mV	120.4V	0.254uA	741mV	119.8V	0.248uA

Made By: King Huang

Approval: Peter Yang



# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: -55°C/30min, 150°C/30min, for 1000 Cycle

Test Date: 2018.07.04 ~ 2018.08.28

Test Standard : JESD22 STANDER Method-A104

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	749mV	118.5V	0.029uA	741mV	115.2V	0.017uA
2	742mV	118.6V	0.213uA	747mV	116.6V	0.208uA
3	748mV	120.3V	0.178uA	750mV	119.6V	0.285uA
4	749mV	116.8V	0.191uA	740mV	119.2V	0.212uA
5	749mV	115.9V	0.192uA	749mV	115.1V	0.152uA
6	753mV	117.2V	0.283uA	744mV	118.9V	0.289uA
7	742mV	115.7V	0.269uA	751mV	119.8V	0.223uA
8	751mV	120.0V	0.246uA	749mV	120.4V	0.250uA
9	748mV	119.7V	0.282uA	752mV	117.2V	0.240uA
10	753mV	120.5V	0.211uA	751mV	117.6V	0.205uA
11	749mV	116.0V	0.234uA	751mV	118.1V	0.253uA
12	754mV	118.0V	0.190uA	751mV	115.6V	0.258uA
13	742mV	118.6V	0.243uA	753mV	118.2V	0.200uA
14	743mV	119.0V	0.266uA	747mV	118.8V	0.259uA
15	749mV	119.6V	0.274uA	748mV	119.9V	0.185uA
16	754mV	117.1V	0.269uA	747mV	115.2V	0.194uA
17	743mV	116.6V	0.204uA	741mV	115.3V	0.247uA
18	751mV	117.3V	0.193uA	748mV	115.4V	0.289uA
19	744mV	116.1V	0.188uA	751mV	117.6V	0.165uA
20	751mV	116.0V	0.281uA	753mV	115.9V	0.225uA
21	741mV	116.6V	0.188uA	748mV	119.0V	0.282uA
22	744mV	117.7V	0.191uA	754mV	116.1V	0.266uA
23	751mV	116.8V	0.193uA	741mV	116.5V	0.235uA
24	749mV	115.4V	0.168uA	744mV	116.6V	0.287uA
25	742mV	116.9V	0.175uA	748mV	120.2V	0.162uA
26	743mV	116.4V	0.204uA	755mV	119.7V	0.248uA
27	749mV	119.7V	0.184uA	744mV	119.5V	0.206uA
28	744mV	117.6V	0.234uA	746mV	116.8V	0.212uA
29	745mV	120.9V	0.233uA	754mV	119.6V	0.166uA
30	752mV	120.8V	0.279uA	755mV	119.3V	0.170uA
31	741mV	120.5V	0.192uA	751mV	120.8V	0.232uA
32	740mV	119.7V	0.185uA	743mV	119.5V	0.271uA
33	745mV	119.3V	0.290uA	754mV	115.4V	0.252uA
34	755mV	117.3V	0.274uA	753mV	116.8V	0.230uA



# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: -55°C/30min, 150°C/30min, for 1000 Cycle

Test Date: 2018.07.04 ~ 2018.08.28

Test Standard : JESD22 STANDER Method-A104

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	749mV	116.1V	0.214uA	753mV	120.0V	0.280uA
36	741mV	119.7V	0.165uA	754mV	116.9V	0.281uA
37	753mV	119.2V	0.249uA	751mV	116.1V	0.273uA
38	749mV	119.1V	0.233uA	755mV	117.8V	0.161uA
39	748mV	117.3V	0.238uA	749mV	117.4V	0.182uA
40	753mV	115.7V	0.240uA	754mV	120.7V	0.257uA
41	751mV	120.9V	0.169uA	749mV	117.7V	0.235uA
42	740mV	120.7V	0.253uA	743mV	120.3V	0.169uA
43	750mV	119.0V	0.216uA	743mV	121.0V	0.287uA
44	751mV	116.4V	0.197uA	745mV	119.2V	0.187uA
45	755mV	119.9V	0.183uA	743mV	115.4V	0.157uA
46	748mV	119.5V	0.247uA	743mV	115.9V	0.287uA
47	754mV	118.6V	0.157uA	755mV	117.7V	0.165uA
48	745mV	118.5V	0.279uA	754mV	115.0V	0.245uA
49	744mV	115.6V	0.228uA	745mV	115.4V	0.185uA
50	746mV	119.1V	0.289uA	744mV	120.0V	0.214uA
51	740mV	115.8V	0.273uA	751mV	117.5V	0.236uA
52	754mV	117.6V	0.219uA	747mV	118.8V	0.217uA
53	743mV	118.3V	0.182uA	751mV	115.6V	0.214uA
54	744mV	120.8V	0.272uA	753mV	118.3V	0.249uA
55	749mV	120.3V	0.265uA	750mV	118.0V	0.237uA
56	752mV	115.4V	0.176uA	745mV	120.6V	0.214uA
57	748mV	121.0V	0.267uA	740mV	120.9V	0.164uA
58	752mV	119.4V	0.253uA	744mV	117.4V	0.275uA
59	745mV	117.7V	0.266uA	751mV	119.4V	0.236uA
60	744mV	115.6V	0.225uA	753mV	116.5V	0.154uA
61	746mV	119.3V	0.194uA	753mV	120.6V	0.155uA
62	742mV	120.1V	0.271uA	742mV	120.2V	0.189uA
63	743mV	118.1V	0.191uA	747mV	120.0V	0.267uA
64	744mV	120.0V	0.256uA	747mV	115.0V	0.273uA
65	753mV	116.7V	0.242uA	748mV	115.4V	0.290uA
66	743mV	119.1V	0.188uA	755mV	119.1V	0.213uA
67	746mV	120.2V	0.170uA	748mV	117.9V	0.261uA
68	740mV	117.8V	0.189uA	752mV	119.1V	0.173uA



# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: -55°C/30min, 150°C/30min, for 1000 Cycle

Test Date: 2018.07.04 ~ 2018.08.28

Test Standard : JESD22 STANDER Method-A104

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	747mV	117.7V	0.153uA	742mV	120.0V	0.261uA
70	750mV	120.6V	0.289uA	754mV	118.5V	0.165uA
71	744mV	118.8V	0.258uA	749mV	119.7V	0.267uA
72	752mV	116.1V	0.249uA	741mV	120.7V	0.201uA
73	745mV	117.1V	0.279uA	755mV	115.5V	0.275uA
74	748mV	119.5V	0.257uA	748mV	115.0V	0.251uA
75	749mV	118.0V	0.282uA	746mV	120.7V	0.254uA
76	750mV	118.5V	0.160uA	744mV	116.3V	0.267uA
77	744mV	118.7V	0.162uA	753mV	117.3V	0.224uA

Made By: King Huang

Approval: Peter Yang





## High Temperature High Humidity Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 85±2°C , 85±5%RH, 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	752mV	120.8V	0.023uA	754mV	120.4V	0.016uA
2	753mV	119.5V	0.180uA	752mV	115.8V	0.241uA
3	741mV	117.7V	0.162uA	740mV	115.0V	0.248uA
4	745mV	120.3V	0.163uA	744mV	120.3V	0.173uA
5	746mV	116.3V	0.154uA	745mV	119.8V	0.276uA
6	755mV	115.5V	0.224uA	750mV	119.1V	0.207uA
7	745mV	119.5V	0.264uA	745mV	116.8V	0.239uA
8	749mV	115.8V	0.246uA	747mV	119.3V	0.226uA
9	747mV	118.4V	0.152uA	750mV	115.8V	0.151uA
10	744mV	120.7V	0.165uA	748mV	116.8V	0.199uA
11	742mV	116.1V	0.246uA	751mV	120.2V	0.216uA
12	754mV	116.9V	0.170uA	747mV	116.8V	0.233uA
13	745mV	118.2V	0.196uA	752mV	120.4V	0.263uA
14	751mV	119.9V	0.152uA	753mV	118.5V	0.206uA
15	745mV	118.8V	0.162uA	751mV	116.8V	0.283uA
16	755mV	119.1V	0.223uA	746mV	119.0V	0.274uA
17	744mV	119.5V	0.162uA	753mV	115.6V	0.228uA
18	745mV	117.7V	0.247uA	742mV	116.7V	0.154uA
19	745mV	120.1V	0.254uA	743mV	116.6V	0.282uA
20	749mV	117.6V	0.171uA	751mV	115.9V	0.227uA
21	746mV	115.7V	0.236uA	749mV	119.0V	0.237uA
22	749mV	116.4V	0.180uA	748mV	120.5V	0.255uA
23	742mV	115.5V	0.252uA	743mV	120.1V	0.207uA
24	745mV	120.2V	0.221uA	751mV	120.5V	0.238uA
25	748mV	118.0V	0.182uA	747mV	118.5V	0.151uA
26	749mV	116.2V	0.231uA	748mV	117.5V	0.245uA
27	749mV	116.4V	0.183uA	754mV	118.6V	0.210uA
28	750mV	118.9V	0.246uA	754mV	117.3V	0.151uA
29	749mV	115.5V	0.287uA	752mV	115.5V	0.184uA
30	747mV	118.7V	0.169uA	751mV	118.2V	0.226uA
31	750mV	115.2V	0.194uA	746mV	120.7V	0.272uA
32	743mV	115.6V	0.289uA	745mV	119.6V	0.252uA
33	748mV	116.9V	0.203uA	750mV	118.6V	0.166uA
34	741mV	116.8V	0.239uA	743mV	120.0V	0.197uA



## High Temperature High Humidity Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 85±2°C , 85±5%RH, 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	742mV	115.1V	0.263uA	755mV	119.6V	0.160uA
36	741mV	117.7V	0.169uA	740mV	115.1V	0.276uA
37	748mV	119.2V	0.269uA	752mV	117.6V	0.192uA
38	752mV	116.3V	0.241uA	754mV	115.9V	0.168uA
39	744mV	119.9V	0.203uA	753mV	115.4V	0.185uA
40	741mV	116.3V	0.202uA	744mV	120.7V	0.185uA
41	743mV	118.1V	0.235uA	747mV	118.6V	0.286uA
42	749mV	120.3V	0.267uA	752mV	115.5V	0.224uA
43	741mV	120.2V	0.220uA	751mV	120.5V	0.255uA
44	741mV	120.1V	0.227uA	746mV	115.5V	0.217uA
45	741mV	115.8V	0.289uA	752mV	120.2V	0.239uA
46	747mV	120.4V	0.170uA	741mV	116.1V	0.210uA
47	754mV	119.0V	0.241uA	746mV	118.8V	0.191uA
48	746mV	120.3V	0.159uA	742mV	118.1V	0.220uA
49	743mV	118.3V	0.261uA	744mV	116.5V	0.288uA
50	754mV	119.2V	0.278uA	744mV	120.0V	0.269uA
51	744mV	118.2V	0.220uA	752mV	117.4V	0.278uA
52	745mV	115.4V	0.244uA	753mV	118.3V	0.287uA
53	747mV	115.5V	0.212uA	745mV	119.9V	0.218uA
54	754mV	118.5V	0.289uA	749mV	120.0V	0.187uA
55	742mV	115.7V	0.241uA	745mV	115.6V	0.201uA
56	747mV	119.1V	0.200uA	753mV	115.0V	0.251uA
57	750mV	115.3V	0.258uA	744mV	117.4V	0.188uA
58	742mV	120.4V	0.274uA	745mV	119.5V	0.249uA
59	742mV	116.0V	0.211uA	743mV	115.3V	0.270uA
60	753mV	119.2V	0.260uA	752mV	117.3V	0.170uA
61	742mV	120.4V	0.256uA	749mV	120.1V	0.238uA
62	749mV	115.5V	0.257uA	740mV	120.2V	0.229uA
63	750mV	118.2V	0.201uA	741mV	117.9V	0.239uA
64	747mV	115.2V	0.264uA	746mV	118.2V	0.262uA
65	747mV	116.6V	0.281uA	742mV	116.2V	0.240uA
66	752mV	118.1V	0.211uA	746mV	116.9V	0.189uA
67	746mV	117.7V	0.224uA	744mV	115.7V	0.231uA
68	743mV	120.2V	0.222uA	749mV	118.9V	0.162uA



# SeCoS Corporation

## High Temperature High Humidity Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 85±2°C , 85±5%RH, 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	745mV	116.4V	0.184uA	740mV	116.3V	0.272uA
70	742mV	118.2V	0.231uA	748mV	117.6V	0.216uA
71	745mV	117.5V	0.233uA	740mV	118.1V	0.245uA
72	746mV	115.7V	0.274uA	746mV	119.1V	0.200uA
73	752mV	118.1V	0.275uA	753mV	118.5V	0.230uA
74	752mV	118.0V	0.160uA	743mV	118.7V	0.176uA
75	742mV	115.2V	0.216uA	743mV	117.5V	0.271uA
76	752mV	117.1V	0.224uA	749mV	119.4V	0.186uA
77	751mV	116.1V	0.179uA	749mV	116.3V	0.188uA

Made By: King Huang

Approval: Peter Yang



## High Temperature High Humidity Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 85±2°C , 85±5%RH, 80% VR 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	750mV	119.6V	0.025uA	746mV	115.2V	0.028uA
2	751mV	116.7V	0.246uA	741mV	116.9V	0.171uA
3	755mV	116.8V	0.287uA	741mV	120.2V	0.236uA
4	753mV	116.3V	0.206uA	742mV	115.6V	0.258uA
5	747mV	116.2V	0.235uA	754mV	119.1V	0.232uA
6	744mV	120.7V	0.172uA	746mV	116.4V	0.178uA
7	741mV	115.1V	0.152uA	743mV	117.2V	0.274uA
8	751mV	118.8V	0.184uA	750mV	119.6V	0.169uA
9	749mV	116.8V	0.264uA	751mV	120.5V	0.241uA
10	740mV	118.4V	0.167uA	745mV	115.6V	0.262uA
11	753mV	119.2V	0.210uA	755mV	116.3V	0.179uA
12	753mV	117.8V	0.272uA	740mV	115.8V	0.152uA
13	743mV	119.2V	0.233uA	742mV	116.7V	0.255uA
14	750mV	120.4V	0.163uA	747mV	117.5V	0.199uA
15	743mV	119.6V	0.241uA	751mV	118.9V	0.264uA
16	754mV	119.9V	0.177uA	753mV	119.9V	0.262uA
17	747mV	119.2V	0.260uA	745mV	117.8V	0.258uA
18	745mV	118.9V	0.215uA	743mV	116.3V	0.214uA
19	749mV	118.1V	0.243uA	741mV	120.2V	0.167uA
20	749mV	116.8V	0.161uA	752mV	118.9V	0.281uA
21	745mV	117.9V	0.263uA	740mV	120.7V	0.154uA
22	752mV	115.9V	0.284uA	748mV	118.4V	0.280uA
23	755mV	116.3V	0.223uA	743mV	120.3V	0.165uA
24	750mV	119.4V	0.179uA	740mV	115.0V	0.232uA
25	748mV	115.6V	0.286uA	754mV	120.6V	0.280uA
26	751mV	118.1V	0.218uA	750mV	115.1V	0.185uA
27	748mV	115.4V	0.216uA	746mV	116.0V	0.235uA
28	747mV	117.5V	0.169uA	744mV	116.4V	0.247uA
29	748mV	115.4V	0.217uA	744mV	118.5V	0.219uA
30	754mV	120.2V	0.289uA	743mV	117.0V	0.211uA
31	753mV	119.6V	0.232uA	755mV	119.5V	0.260uA
32	754mV	116.5V	0.158uA	752mV	120.3V	0.166uA
33	750mV	117.3V	0.171uA	747mV	120.2V	0.211uA
34	740mV	115.4V	0.176uA	746mV	119.6V	0.197uA



## High Temperature High Humidity Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 85±2°C , 85±5%RH, 80% VR 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	740mV	119.4V	0.173uA	747mV	115.2V	0.286uA
36	753mV	121.0V	0.151uA	740mV	119.6V	0.169uA
37	755mV	117.5V	0.247uA	747mV	115.2V	0.194uA
38	745mV	119.3V	0.250uA	743mV	119.6V	0.175uA
39	752mV	119.4V	0.173uA	751mV	115.6V	0.288uA
40	750mV	116.8V	0.243uA	749mV	116.8V	0.231uA
41	743mV	116.4V	0.238uA	747mV	119.4V	0.212uA
42	742mV	120.5V	0.197uA	750mV	119.4V	0.230uA
43	744mV	119.9V	0.277uA	744mV	117.1V	0.248uA
44	741mV	118.8V	0.285uA	740mV	119.9V	0.266uA
45	755mV	118.3V	0.173uA	741mV	119.2V	0.169uA
46	751mV	120.0V	0.233uA	742mV	120.4V	0.285uA
47	747mV	119.0V	0.266uA	752mV	121.0V	0.238uA
48	741mV	116.8V	0.289uA	755mV	116.6V	0.210uA
49	750mV	118.3V	0.206uA	755mV	117.2V	0.262uA
50	746mV	117.8V	0.234uA	745mV	116.0V	0.230uA
51	754mV	118.7V	0.214uA	749mV	117.9V	0.263uA
52	754mV	120.8V	0.185uA	752mV	120.2V	0.274uA
53	750mV	119.2V	0.195uA	741mV	115.5V	0.254uA
54	745mV	115.8V	0.172uA	754mV	118.0V	0.260uA
55	748mV	119.7V	0.163uA	744mV	119.5V	0.236uA
56	746mV	118.5V	0.233uA	741mV	116.0V	0.256uA
57	748mV	116.4V	0.279uA	742mV	117.7V	0.211uA
58	751mV	120.5V	0.253uA	751mV	117.1V	0.193uA
59	742mV	116.0V	0.186uA	742mV	115.4V	0.207uA
60	752mV	117.9V	0.219uA	754mV	115.7V	0.175uA
61	745mV	115.3V	0.249uA	754mV	116.2V	0.172uA
62	742mV	116.7V	0.259uA	750mV	116.4V	0.172uA
63	741mV	120.5V	0.207uA	749mV	120.2V	0.267uA
64	741mV	116.2V	0.288uA	741mV	116.0V	0.155uA
65	749mV	117.0V	0.250uA	748mV	120.4V	0.218uA
66	745mV	118.3V	0.151uA	750mV	117.6V	0.171uA
67	749mV	116.0V	0.175uA	745mV	119.5V	0.235uA
68	746mV	116.9V	0.188uA	753mV	117.1V	0.258uA



# SeCoS Corporation

## High Temperature High Humidity Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 85±2°C , 85±5%RH, 80% VR 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	753mV	119.4V	0.166uA	752mV	115.5V	0.195uA
70	754mV	120.6V	0.287uA	741mV	120.5V	0.160uA
71	750mV	116.2V	0.274uA	751mV	117.7V	0.173uA
72	753mV	120.9V	0.246uA	746mV	118.0V	0.207uA
73	746mV	116.7V	0.214uA	744mV	116.8V	0.272uA
74	753mV	119.8V	0.253uA	748mV	117.7V	0.264uA
75	752mV	115.3V	0.186uA	742mV	118.7V	0.223uA
76	752mV	120.6V	0.162uA	741mV	116.1V	0.233uA
77	752mV	119.6V	0.186uA	741mV	115.8V	0.208uA

Made By: King Huang

Approval: Peter Yang



# SeCoS Corporation

## Solderability Test Data

Report No : T180702-5100B

Part No : SM5100B-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<820mV@IF=5A ; VBR>100V@I1=1mA

IR<100uA@VR=100V

Test Condition: 245 ± 5°C, 5Sec

Test Date: 2018.08.27

Test Standard : JESD22 STANDER Method-B102

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	755mV	120.6V	0.024uA	744mV	115.5V	0.016uA
2	750mV	117.3V	0.243uA	744mV	118.5V	0.248uA
3	746mV	120.7V	0.259uA	745mV	119.8V	0.266uA
4	748mV	120.5V	0.224uA	746mV	116.8V	0.153uA
5	744mV	116.8V	0.270uA	751mV	115.9V	0.240uA
6	741mV	116.7V	0.264uA	752mV	118.8V	0.283uA
7	742mV	116.3V	0.176uA	741mV	116.1V	0.263uA
8	750mV	119.7V	0.230uA	742mV	120.3V	0.188uA
9	754mV	116.0V	0.210uA	749mV	115.5V	0.218uA
10	751mV	118.8V	0.263uA	751mV	116.0V	0.153uA

Made By: King Huang

Approval: Peter Yang





## Reliability Testing Summary Report

Date: 2018/08/31

Document No.: SL18-07-8200C

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SM8200C-C	100±5°C, 80% VR, T=1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SM8200C-C	150°C, T=1000hrs		77	0	0	ACC
PCT Pressure Cooker Test	SM8200C-C	121°C, 29.7PSIG, 168hrs		77	0	0	ACC
TCT Temperature Cycle Test	SM8200C-C	-55°C/30min, 150°C/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SM8200C-C	85 ± 2°C, RH=85±5%, 1000hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SM8200C-C	85 ± 2°C, RH=85±5%, 80% VR, 1000hrs		77	0	0	ACC
Solderability	SM8200C-C	245 ± 5°C, 5Sec the inspected area of each lead must have 95% solder coverage minimum		10	0	0	ACC

**Judgment:**

qualified     unqualified

Testing Start Date: 2018.07.01    Testing End Date: 2018.08.31

Tester: King Huang    Approval: Peter Yang



## Electrical Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 25°C

Test Date: 2018.07.02

Test Standard : Specifications

Operator: Joe Lee

Test Result: PASS

No	VF (mV)	VBR (V)	IR (uA)
1	850mV	220.7V	0.018uA
2	850mV	222.7V	0.016uA
3	850mV	216.7V	0.020uA
4	853mV	215.2V	0.025uA
5	850mV	220.0V	0.020uA
6	847mV	215.9V	0.023uA
7	841mV	223.3V	0.027uA
8	855mV	219.1V	0.028uA
9	844mV	218.7V	0.020uA
10	847mV	219.8V	0.017uA
11	843mV	223.4V	0.023uA
12	843mV	223.0V	0.015uA
13	852mV	216.4V	0.022uA
14	847mV	217.1V	0.019uA
15	852mV	219.2V	0.018uA
16	854mV	217.6V	0.022uA
17	852mV	220.7V	0.027uA
18	851mV	222.8V	0.020uA
19	841mV	218.8V	0.022uA
20	845mV	215.5V	0.029uA
21	843mV	217.1V	0.024uA
22	854mV	221.1V	0.015uA
23	851mV	219.8V	0.017uA
24	849mV	221.8V	0.016uA
25	853mV	223.5V	0.019uA
26	841mV	222.9V	0.025uA
27	841mV	218.5V	0.016uA
28	841mV	222.8V	0.018uA
29	854mV	215.7V	0.021uA
30	845mV	222.2V	0.016uA
31	857mV	215.3V	0.025uA
32	848mV	217.3V	0.018uA
33	841mV	218.3V	0.026uA
34	848mV	223.1V	0.025uA
35	842mV	217.1V	0.019uA



## Electrical Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 25°C

Test Date: 2018.07.02

Test Standard : Specifications

Operator: Joe Lee

Test Result: PASS

No	VF (mV)	VBR (V)	IR (uA)
36	853mV	220.7V	0.029uA
37	855mV	217.5V	0.028uA
38	848mV	218.2V	0.017uA
39	842mV	217.2V	0.018uA
40	855mV	222.5V	0.028uA
41	853mV	216.6V	0.028uA
42	858mV	216.7V	0.025uA
43	855mV	220.5V	0.029uA
44	847mV	217.2V	0.015uA
45	849mV	217.2V	0.019uA
46	856mV	222.5V	0.027uA
47	856mV	218.4V	0.023uA
48	845mV	217.5V	0.023uA
49	857mV	223.8V	0.024uA
50	853mV	218.4V	0.018uA
51	842mV	222.3V	0.024uA
52	851mV	216.4V	0.025uA
53	855mV	218.9V	0.022uA
54	848mV	215.0V	0.019uA
55	856mV	220.4V	0.023uA
56	851mV	215.6V	0.025uA
57	851mV	219.7V	0.027uA
58	844mV	223.1V	0.021uA
59	842mV	215.5V	0.020uA
60	843mV	220.2V	0.025uA
61	854mV	220.5V	0.022uA
62	846mV	215.5V	0.020uA
63	854mV	218.0V	0.019uA
64	840mV	215.3V	0.023uA
65	848mV	219.1V	0.021uA
66	845mV	215.3V	0.026uA
67	845mV	220.8V	0.028uA
68	846mV	218.4V	0.017uA
69	850mV	223.2V	0.020uA
70	849mV	221.6V	0.018uA



# SeCoS Corporation

## Electrical Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 25°C

Test Date: 2018.07.02

Test Standard : Specifications

Operator: Joe Lee

Test Result: PASS

No	VF (mV)	VBR (V)	IR (uA)
71	847mV	217.2V	0.015uA
72	840mV	220.3V	0.019uA
73	855mV	218.9V	0.022uA
74	853mV	221.0V	0.017uA
75	844mV	219.9V	0.026uA
76	858mV	223.5V	0.023uA
77	853mV	217.6V	0.026uA

Made By: King Huang

Approval: Peter Yang



## High Temperature Reverse Bias Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 100±5°C , 80% VR, T=1000hrs

Test Date: 2018.07.03 ~ 2018.08.14

Test Standard : JESD22 STANDER Method-A108

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	839mV	215.7V	0.028uA	854mV	219.0V	0.016uA
2	848mV	216.3V	0.017uA	849mV	219.3V	0.021uA
3	856mV	215.7V	0.017uA	848mV	217.5V	0.028uA
4	841mV	218.4V	0.019uA	844mV	217.2V	0.020uA
5	852mV	218.5V	0.022uA	851mV	221.2V	0.022uA
6	849mV	215.0V	0.024uA	843mV	219.4V	0.026uA
7	839mV	219.8V	0.023uA	851mV	223.8V	0.027uA
8	846mV	220.0V	0.018uA	845mV	222.3V	0.020uA
9	854mV	220.0V	0.021uA	841mV	221.9V	0.027uA
10	845mV	215.9V	0.017uA	852mV	219.7V	0.021uA
11	858mV	223.6V	0.026uA	850mV	220.4V	0.015uA
12	840mV	215.4V	0.015uA	845mV	220.9V	0.020uA
13	840mV	219.3V	0.022uA	847mV	215.3V	0.021uA
14	848mV	219.1V	0.027uA	841mV	220.3V	0.016uA
15	841mV	223.0V	0.022uA	850mV	219.9V	0.025uA
16	842mV	216.6V	0.021uA	857mV	221.8V	0.028uA
17	850mV	222.9V	0.026uA	848mV	217.5V	0.022uA
18	847mV	218.8V	0.024uA	849mV	222.0V	0.022uA
19	842mV	221.6V	0.027uA	852mV	222.8V	0.020uA
20	850mV	217.8V	0.021uA	856mV	219.2V	0.020uA
21	854mV	221.1V	0.025uA	857mV	219.0V	0.019uA
22	853mV	217.5V	0.023uA	841mV	223.8V	0.024uA
23	850mV	215.1V	0.019uA	846mV	219.5V	0.017uA
24	848mV	223.1V	0.016uA	841mV	220.2V	0.028uA
25	858mV	219.2V	0.029uA	852mV	218.3V	0.017uA
26	840mV	216.9V	0.019uA	848mV	220.2V	0.024uA
27	856mV	217.3V	0.019uA	845mV	223.5V	0.018uA
28	848mV	216.1V	0.022uA	855mV	223.9V	0.017uA
29	849mV	218.3V	0.022uA	852mV	219.7V	0.028uA
30	852mV	221.4V	0.018uA	843mV	215.9V	0.022uA
31	846mV	216.8V	0.026uA	847mV	219.4V	0.029uA
32	854mV	221.8V	0.016uA	857mV	221.8V	0.015uA
33	844mV	221.3V	0.022uA	844mV	222.7V	0.018uA
34	847mV	223.3V	0.025uA	849mV	218.2V	0.029uA



# SeCoS Corporation

## High Temperature Reverse Bias Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 100±5°C , 80% VR, T=1000hrs

Test Date: 2018.07.03 ~ 2018.08.14

Test Standard : JESD22 STANDER Method-A108

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	852mV	222.8V	0.017uA	850mV	222.4V	0.020uA
36	844mV	223.0V	0.027uA	850mV	216.7V	0.027uA
37	854mV	216.1V	0.023uA	840mV	221.3V	0.025uA
38	848mV	216.4V	0.028uA	855mV	219.2V	0.025uA
39	857mV	220.0V	0.022uA	854mV	219.9V	0.019uA
40	850mV	218.4V	0.027uA	844mV	218.0V	0.016uA
41	843mV	220.0V	0.017uA	852mV	219.8V	0.027uA
42	850mV	220.1V	0.016uA	842mV	219.2V	0.026uA
43	853mV	218.5V	0.025uA	840mV	218.1V	0.026uA
44	839mV	217.1V	0.017uA	855mV	223.7V	0.022uA
45	851mV	215.3V	0.021uA	843mV	223.0V	0.021uA
46	854mV	223.2V	0.021uA	843mV	216.5V	0.028uA
47	856mV	223.3V	0.019uA	850mV	222.9V	0.016uA
48	841mV	216.9V	0.019uA	843mV	215.2V	0.017uA
49	852mV	223.5V	0.025uA	856mV	218.9V	0.027uA
50	850mV	217.8V	0.022uA	848mV	220.5V	0.020uA
51	846mV	220.7V	0.016uA	851mV	222.3V	0.021uA
52	841mV	218.0V	0.024uA	845mV	223.5V	0.020uA
53	849mV	215.1V	0.021uA	840mV	221.9V	0.026uA
54	845mV	219.6V	0.019uA	856mV	216.0V	0.022uA
55	843mV	223.1V	0.029uA	857mV	222.2V	0.016uA
56	842mV	216.6V	0.019uA	856mV	218.6V	0.020uA
57	845mV	216.2V	0.028uA	840mV	216.2V	0.016uA
58	845mV	223.3V	0.016uA	855mV	221.0V	0.018uA
59	839mV	215.0V	0.019uA	855mV	215.2V	0.028uA
60	841mV	215.3V	0.025uA	854mV	217.6V	0.020uA
61	852mV	219.2V	0.018uA	853mV	222.4V	0.025uA
62	844mV	221.7V	0.027uA	840mV	218.2V	0.018uA
63	848mV	220.3V	0.015uA	857mV	222.2V	0.017uA
64	843mV	223.9V	0.023uA	858mV	218.4V	0.025uA
65	839mV	223.4V	0.017uA	851mV	216.7V	0.021uA
66	853mV	217.3V	0.025uA	854mV	222.7V	0.022uA
67	847mV	223.8V	0.028uA	852mV	219.3V	0.024uA
68	858mV	220.6V	0.020uA	854mV	223.5V	0.017uA



# SeCoS Corporation

## High Temperature Reverse Bias Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 100±5°C , 80% VR, T=1000hrs

Test Date: 2018.07.03 ~ 2018.08.14

Test Standard : JESD22 STANDER Method-A108

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	849mV	223.4V	0.016uA	850mV	220.4V	0.020uA
70	858mV	219.4V	0.024uA	847mV	220.7V	0.020uA
71	852mV	217.4V	0.018uA	854mV	220.0V	0.019uA
72	851mV	223.5V	0.015uA	840mV	218.3V	0.026uA
73	848mV	215.7V	0.017uA	855mV	216.0V	0.015uA
74	858mV	215.2V	0.027uA	853mV	215.4V	0.017uA
75	849mV	216.3V	0.020uA	848mV	216.6V	0.021uA
76	842mV	220.6V	0.026uA	849mV	217.1V	0.023uA
77	856mV	224.0V	0.026uA	852mV	223.1V	0.022uA

Made By: King Huang

Approval: Peter Yang





## High Temperature Storage Life Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 150°C, T=1000hrs

Test Date: 2018.07.04 ~ 2018.08.15

Test Standard : JESD22 STANDER Method-A103

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	849mV	215.6V	0.029uA	847mV	223.9V	0.025uA
2	839mV	217.6V	0.020uA	851mV	220.0V	0.029uA
3	841mV	219.2V	0.024uA	851mV	217.7V	0.022uA
4	854mV	221.8V	0.021uA	846mV	221.0V	0.024uA
5	855mV	221.0V	0.021uA	845mV	222.9V	0.023uA
6	840mV	223.6V	0.015uA	844mV	219.1V	0.023uA
7	847mV	220.5V	0.025uA	847mV	216.2V	0.022uA
8	843mV	218.8V	0.025uA	849mV	216.3V	0.016uA
9	845mV	222.3V	0.024uA	849mV	217.4V	0.026uA
10	853mV	221.8V	0.017uA	848mV	220.4V	0.026uA
11	849mV	222.6V	0.027uA	841mV	218.5V	0.021uA
12	855mV	221.9V	0.026uA	844mV	217.2V	0.019uA
13	846mV	221.2V	0.025uA	852mV	220.3V	0.016uA
14	848mV	219.3V	0.027uA	853mV	221.4V	0.029uA
15	853mV	221.2V	0.017uA	845mV	215.7V	0.019uA
16	855mV	217.0V	0.016uA	851mV	217.1V	0.025uA
17	852mV	221.3V	0.015uA	845mV	220.0V	0.027uA
18	851mV	222.2V	0.021uA	843mV	217.0V	0.021uA
19	851mV	217.7V	0.028uA	848mV	221.1V	0.028uA
20	855mV	219.2V	0.028uA	850mV	223.1V	0.026uA
21	844mV	215.4V	0.028uA	848mV	216.9V	0.028uA
22	851mV	223.6V	0.023uA	841mV	217.6V	0.025uA
23	850mV	215.7V	0.027uA	853mV	221.1V	0.016uA
24	849mV	217.0V	0.024uA	841mV	223.4V	0.027uA
25	854mV	220.0V	0.022uA	844mV	218.4V	0.021uA
26	854mV	221.3V	0.016uA	850mV	215.0V	0.021uA
27	842mV	219.3V	0.022uA	843mV	222.6V	0.016uA
28	851mV	215.6V	0.027uA	850mV	220.9V	0.018uA
29	844mV	221.7V	0.017uA	843mV	215.9V	0.023uA
30	857mV	218.0V	0.029uA	839mV	216.3V	0.028uA
31	849mV	216.7V	0.020uA	852mV	223.2V	0.016uA
32	850mV	220.5V	0.027uA	844mV	216.8V	0.028uA
33	846mV	215.9V	0.020uA	843mV	216.8V	0.026uA
34	850mV	218.8V	0.021uA	852mV	219.5V	0.026uA



## High Temperature Storage Life Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 150°C, T=1000hrs

Test Date: 2018.07.04 ~ 2018.08.15

Test Standard : JESD22 STANDER Method-A103

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	853mV	218.7V	0.025uA	851mV	218.0V	0.026uA
36	844mV	217.4V	0.023uA	840mV	219.4V	0.025uA
37	841mV	216.3V	0.026uA	851mV	223.5V	0.020uA
38	851mV	220.3V	0.028uA	849mV	219.1V	0.026uA
39	846mV	217.7V	0.024uA	841mV	215.7V	0.017uA
40	840mV	216.0V	0.020uA	842mV	216.7V	0.023uA
41	844mV	220.6V	0.016uA	845mV	215.1V	0.019uA
42	847mV	220.3V	0.020uA	851mV	216.5V	0.027uA
43	856mV	216.9V	0.022uA	845mV	218.7V	0.019uA
44	844mV	220.1V	0.017uA	848mV	217.7V	0.016uA
45	850mV	221.5V	0.022uA	845mV	223.8V	0.017uA
46	857mV	220.2V	0.026uA	846mV	218.6V	0.018uA
47	852mV	221.8V	0.022uA	844mV	218.1V	0.019uA
48	849mV	215.5V	0.021uA	852mV	223.2V	0.017uA
49	852mV	217.4V	0.022uA	850mV	221.8V	0.021uA
50	852mV	221.6V	0.025uA	845mV	216.8V	0.026uA
51	857mV	220.4V	0.027uA	845mV	218.7V	0.018uA
52	844mV	219.2V	0.019uA	841mV	218.5V	0.018uA
53	846mV	218.3V	0.028uA	854mV	221.5V	0.020uA
54	856mV	216.3V	0.016uA	856mV	222.0V	0.029uA
55	853mV	223.3V	0.021uA	853mV	223.2V	0.019uA
56	842mV	221.2V	0.027uA	855mV	221.3V	0.029uA
57	849mV	219.6V	0.022uA	849mV	223.8V	0.022uA
58	856mV	216.2V	0.028uA	858mV	222.1V	0.019uA
59	855mV	219.0V	0.016uA	856mV	217.6V	0.020uA
60	849mV	223.8V	0.028uA	851mV	217.1V	0.017uA
61	839mV	215.3V	0.027uA	854mV	218.2V	0.026uA
62	850mV	219.0V	0.021uA	854mV	222.8V	0.028uA
63	856mV	222.9V	0.015uA	847mV	220.2V	0.025uA
64	848mV	223.2V	0.016uA	853mV	220.3V	0.023uA
65	853mV	219.0V	0.018uA	840mV	215.8V	0.021uA
66	855mV	219.0V	0.018uA	852mV	217.1V	0.017uA
67	840mV	215.7V	0.022uA	848mV	215.5V	0.016uA
68	841mV	218.8V	0.024uA	844mV	221.1V	0.028uA



# SeCoS Corporation

## High Temperature Storage Life Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 150°C, T=1000hrs

Test Date: 2018.07.04 ~ 2018.08.15

Test Standard : JESD22 STANDER Method-A103

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	845mV	223.9V	0.017uA	842mV	222.8V	0.028uA
70	854mV	222.8V	0.017uA	843mV	222.2V	0.027uA
71	845mV	216.5V	0.027uA	846mV	215.7V	0.028uA
72	844mV	218.2V	0.022uA	858mV	216.7V	0.025uA
73	847mV	220.3V	0.024uA	851mV	221.7V	0.020uA
74	857mV	216.4V	0.022uA	851mV	217.6V	0.023uA
75	857mV	215.2V	0.028uA	845mV	217.0V	0.020uA
76	845mV	220.0V	0.020uA	854mV	222.9V	0.027uA
77	853mV	215.9V	0.027uA	841mV	219.8V	0.025uA

Made By: King Huang

Approval: Peter Yang



# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 121°C , 29.7PSIG, 168Hrs

Test Date: 2018.07.31 ~ 2018.08.08

Test Standard : JESD22 STANDER Method-A102

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	850mV	220.6V	0.029uA	841mV	217.4V	0.019uA
2	847mV	216.7V	0.019uA	855mV	219.8V	0.023uA
3	852mV	221.4V	0.015uA	854mV	223.3V	0.020uA
4	845mV	215.5V	0.021uA	850mV	217.4V	0.020uA
5	857mV	215.3V	0.016uA	845mV	216.2V	0.019uA
6	855mV	221.5V	0.022uA	842mV	221.6V	0.017uA
7	842mV	223.5V	0.021uA	848mV	222.6V	0.019uA
8	841mV	222.9V	0.026uA	848mV	217.0V	0.019uA
9	841mV	216.8V	0.025uA	851mV	221.1V	0.028uA
10	840mV	215.7V	0.028uA	857mV	222.4V	0.017uA
11	845mV	219.2V	0.021uA	855mV	221.5V	0.018uA
12	851mV	220.4V	0.023uA	844mV	222.1V	0.024uA
13	849mV	218.3V	0.020uA	844mV	223.6V	0.024uA
14	839mV	223.7V	0.026uA	850mV	215.4V	0.018uA
15	844mV	221.6V	0.018uA	845mV	222.7V	0.021uA
16	848mV	218.1V	0.028uA	851mV	224.0V	0.023uA
17	857mV	224.0V	0.028uA	855mV	223.2V	0.018uA
18	850mV	221.9V	0.026uA	842mV	223.4V	0.020uA
19	839mV	222.2V	0.017uA	841mV	223.6V	0.024uA
20	852mV	218.9V	0.017uA	851mV	223.6V	0.016uA
21	840mV	218.8V	0.025uA	842mV	223.5V	0.017uA
22	839mV	216.9V	0.017uA	840mV	219.7V	0.024uA
23	842mV	215.4V	0.025uA	842mV	215.5V	0.016uA
24	843mV	222.0V	0.024uA	842mV	219.5V	0.029uA
25	849mV	216.9V	0.019uA	844mV	223.6V	0.022uA
26	847mV	217.0V	0.023uA	857mV	216.6V	0.017uA
27	852mV	215.3V	0.017uA	855mV	219.0V	0.025uA
28	844mV	216.1V	0.025uA	856mV	223.6V	0.019uA
29	844mV	218.7V	0.015uA	842mV	217.7V	0.028uA
30	844mV	221.7V	0.023uA	841mV	216.6V	0.026uA
31	851mV	216.9V	0.018uA	855mV	222.6V	0.025uA
32	849mV	215.2V	0.028uA	840mV	216.8V	0.022uA
33	850mV	219.4V	0.018uA	853mV	220.4V	0.024uA
34	846mV	216.8V	0.024uA	843mV	217.7V	0.016uA



# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 121°C, 29.7PSIG, 168Hrs

Test Date: 2018.07.31 ~ 2018.08.08

Test Standard : JESD22 STANDER Method-A102

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	846mV	216.7V	0.023uA	856mV	223.1V	0.022uA
36	852mV	220.7V	0.025uA	848mV	217.0V	0.019uA
37	843mV	216.9V	0.022uA	852mV	219.7V	0.024uA
38	853mV	215.5V	0.023uA	847mV	223.3V	0.025uA
39	854mV	219.5V	0.020uA	843mV	215.8V	0.025uA
40	847mV	220.3V	0.020uA	845mV	221.5V	0.027uA
41	847mV	218.5V	0.017uA	857mV	221.2V	0.020uA
42	857mV	218.5V	0.018uA	854mV	219.7V	0.027uA
43	846mV	218.9V	0.024uA	852mV	216.6V	0.028uA
44	839mV	217.7V	0.018uA	846mV	223.3V	0.025uA
45	858mV	219.5V	0.027uA	841mV	217.8V	0.023uA
46	843mV	220.5V	0.021uA	854mV	216.8V	0.024uA
47	848mV	221.3V	0.018uA	839mV	217.3V	0.024uA
48	844mV	215.4V	0.025uA	857mV	216.6V	0.017uA
49	846mV	221.3V	0.022uA	843mV	217.4V	0.015uA
50	855mV	219.7V	0.017uA	844mV	219.1V	0.021uA
51	842mV	223.5V	0.017uA	844mV	219.5V	0.029uA
52	849mV	218.6V	0.021uA	847mV	223.1V	0.022uA
53	853mV	222.1V	0.026uA	850mV	217.7V	0.022uA
54	849mV	218.3V	0.028uA	851mV	220.8V	0.025uA
55	844mV	222.2V	0.026uA	842mV	222.3V	0.026uA
56	846mV	222.1V	0.021uA	852mV	220.9V	0.026uA
57	852mV	215.3V	0.027uA	847mV	216.2V	0.022uA
58	841mV	219.6V	0.019uA	855mV	220.5V	0.025uA
59	852mV	223.8V	0.023uA	854mV	222.9V	0.024uA
60	857mV	218.8V	0.018uA	844mV	219.8V	0.029uA
61	839mV	221.8V	0.028uA	840mV	215.8V	0.020uA
62	844mV	219.5V	0.021uA	854mV	219.2V	0.026uA
63	841mV	221.4V	0.024uA	842mV	223.5V	0.026uA
64	843mV	221.3V	0.028uA	853mV	219.7V	0.027uA
65	850mV	217.3V	0.018uA	839mV	216.9V	0.017uA
66	850mV	215.7V	0.028uA	849mV	219.8V	0.028uA
67	841mV	219.2V	0.015uA	841mV	219.9V	0.027uA
68	853mV	219.9V	0.017uA	850mV	221.5V	0.016uA



# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 121°C, 29.7PSIG, 168Hrs

Test Date: 2018.07.31 ~ 2018.08.08

Test Standard : JESD22 STANDER Method-A102

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	856mV	220.2V	0.020uA	858mV	216.9V	0.022uA
70	839mV	223.8V	0.027uA	852mV	223.6V	0.025uA
71	840mV	218.9V	0.021uA	853mV	220.1V	0.021uA
72	848mV	217.6V	0.023uA	848mV	220.8V	0.016uA
73	848mV	218.3V	0.017uA	839mV	219.6V	0.019uA
74	842mV	218.0V	0.027uA	843mV	217.0V	0.020uA
75	854mV	221.4V	0.020uA	847mV	218.8V	0.025uA
76	845mV	223.0V	0.023uA	852mV	220.2V	0.021uA
77	840mV	224.0V	0.015uA	844mV	215.0V	0.016uA

Made By: King Huang

Approval: Peter Yang



# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: -55°C/30min, 150°C/30min, for 1000 Cycle

Test Date: 2018.07.04 ~ 2018.08.28

Test Standard : JESD22 STANDER Method-A104

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	845mV	222.8V	0.028uA	842mV	218.4V	0.022uA
2	840mV	216.1V	0.024uA	856mV	218.8V	0.022uA
3	853mV	223.1V	0.019uA	841mV	219.7V	0.019uA
4	840mV	221.0V	0.022uA	848mV	216.8V	0.019uA
5	846mV	217.4V	0.019uA	855mV	219.2V	0.026uA
6	850mV	221.1V	0.019uA	850mV	220.1V	0.015uA
7	850mV	222.3V	0.025uA	852mV	216.8V	0.027uA
8	845mV	221.4V	0.015uA	843mV	218.5V	0.023uA
9	855mV	218.8V	0.026uA	843mV	223.9V	0.024uA
10	847mV	219.7V	0.020uA	849mV	223.1V	0.017uA
11	853mV	219.7V	0.020uA	842mV	215.8V	0.023uA
12	839mV	216.4V	0.016uA	851mV	222.5V	0.017uA
13	845mV	223.5V	0.029uA	843mV	220.8V	0.027uA
14	852mV	215.4V	0.022uA	855mV	220.8V	0.023uA
15	849mV	218.1V	0.024uA	847mV	223.5V	0.027uA
16	858mV	217.1V	0.019uA	841mV	224.0V	0.025uA
17	842mV	220.8V	0.023uA	847mV	218.0V	0.029uA
18	848mV	217.6V	0.026uA	858mV	221.7V	0.021uA
19	853mV	218.2V	0.020uA	857mV	221.3V	0.017uA
20	841mV	221.1V	0.020uA	856mV	218.6V	0.018uA
21	856mV	217.7V	0.016uA	849mV	221.9V	0.023uA
22	845mV	216.4V	0.022uA	855mV	221.7V	0.027uA
23	849mV	220.1V	0.016uA	855mV	219.8V	0.023uA
24	856mV	216.6V	0.025uA	842mV	218.8V	0.023uA
25	856mV	221.4V	0.016uA	850mV	220.2V	0.024uA
26	858mV	223.5V	0.018uA	854mV	216.6V	0.026uA
27	854mV	217.3V	0.018uA	842mV	216.4V	0.027uA
28	850mV	222.3V	0.023uA	847mV	219.0V	0.025uA
29	851mV	221.8V	0.021uA	846mV	217.7V	0.026uA
30	842mV	217.7V	0.028uA	854mV	218.0V	0.022uA
31	850mV	217.2V	0.015uA	849mV	219.6V	0.018uA
32	842mV	222.0V	0.022uA	851mV	223.0V	0.016uA
33	852mV	222.2V	0.020uA	847mV	219.4V	0.025uA
34	855mV	217.7V	0.029uA	854mV	221.8V	0.024uA





# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: -55°C/30min, 150°C/30min, for 1000 Cycle

Test Date: 2018.07.04 ~ 2018.08.28

Test Standard : JESD22 STANDER Method-A104

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	855mV	222.0V	0.022uA	845mV	223.4V	0.028uA
36	848mV	218.2V	0.026uA	839mV	221.4V	0.027uA
37	855mV	223.9V	0.022uA	846mV	215.8V	0.021uA
38	847mV	218.2V	0.023uA	839mV	221.1V	0.029uA
39	847mV	217.3V	0.021uA	849mV	217.8V	0.021uA
40	851mV	215.7V	0.025uA	857mV	223.8V	0.028uA
41	852mV	215.1V	0.027uA	855mV	220.8V	0.016uA
42	843mV	223.2V	0.020uA	840mV	216.2V	0.024uA
43	855mV	218.5V	0.017uA	839mV	223.7V	0.022uA
44	842mV	218.5V	0.018uA	855mV	220.2V	0.021uA
45	858mV	222.0V	0.024uA	846mV	220.4V	0.028uA
46	840mV	220.4V	0.016uA	844mV	217.8V	0.018uA
47	850mV	215.1V	0.017uA	842mV	220.6V	0.027uA
48	840mV	220.3V	0.018uA	850mV	223.3V	0.027uA
49	839mV	221.1V	0.021uA	844mV	215.0V	0.017uA
50	850mV	216.9V	0.023uA	852mV	221.7V	0.015uA
51	853mV	215.4V	0.019uA	854mV	222.5V	0.020uA
52	857mV	223.6V	0.026uA	844mV	222.7V	0.023uA
53	844mV	215.7V	0.029uA	844mV	219.7V	0.028uA
54	852mV	217.3V	0.018uA	855mV	217.9V	0.028uA
55	852mV	215.2V	0.019uA	840mV	221.8V	0.019uA
56	843mV	221.8V	0.020uA	841mV	221.8V	0.019uA
57	840mV	220.5V	0.027uA	841mV	218.8V	0.019uA
58	853mV	220.8V	0.022uA	855mV	217.1V	0.029uA
59	845mV	215.4V	0.025uA	842mV	223.6V	0.019uA
60	850mV	219.5V	0.026uA	853mV	221.3V	0.018uA
61	841mV	220.1V	0.027uA	855mV	220.9V	0.019uA
62	853mV	216.1V	0.019uA	848mV	218.4V	0.025uA
63	847mV	216.7V	0.016uA	849mV	220.6V	0.027uA
64	846mV	223.2V	0.019uA	858mV	217.0V	0.018uA
65	840mV	219.2V	0.028uA	839mV	215.4V	0.024uA
66	857mV	218.0V	0.027uA	846mV	223.9V	0.023uA
67	858mV	222.1V	0.026uA	841mV	220.6V	0.021uA
68	841mV	217.8V	0.018uA	855mV	220.6V	0.023uA



# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: -55°C/30min, 150°C/30min, for 1000 Cycle

Test Date: 2018.07.04 ~ 2018.08.28

Test Standard : JESD22 STANDER Method-A104

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	856mV	223.4V	0.017uA	858mV	217.9V	0.023uA
70	848mV	223.0V	0.024uA	852mV	218.0V	0.027uA
71	849mV	217.7V	0.022uA	845mV	222.4V	0.023uA
72	858mV	215.2V	0.022uA	844mV	221.2V	0.021uA
73	852mV	216.9V	0.025uA	853mV	221.9V	0.021uA
74	840mV	223.9V	0.022uA	843mV	223.1V	0.027uA
75	855mV	217.4V	0.027uA	856mV	223.6V	0.029uA
76	856mV	218.4V	0.028uA	855mV	217.4V	0.022uA
77	857mV	218.4V	0.017uA	845mV	221.6V	0.026uA

Made By: King Huang

Approval: Peter Yang



## High Temperature High Humidity Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 85±2°C , 85±5%RH, 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	852mV	219.8V	0.029uA	839mV	219.5V	0.028uA
2	843mV	222.7V	0.028uA	851mV	219.9V	0.028uA
3	848mV	217.0V	0.022uA	840mV	223.6V	0.017uA
4	852mV	216.1V	0.021uA	841mV	221.8V	0.027uA
5	845mV	223.4V	0.020uA	857mV	223.5V	0.022uA
6	852mV	216.0V	0.018uA	857mV	219.5V	0.022uA
7	844mV	223.6V	0.025uA	855mV	223.3V	0.029uA
8	855mV	215.4V	0.021uA	847mV	223.6V	0.022uA
9	845mV	220.1V	0.021uA	849mV	223.3V	0.019uA
10	853mV	221.9V	0.028uA	846mV	222.5V	0.018uA
11	845mV	218.8V	0.018uA	856mV	215.6V	0.025uA
12	846mV	218.7V	0.015uA	855mV	217.5V	0.016uA
13	855mV	220.2V	0.017uA	850mV	215.7V	0.020uA
14	855mV	218.8V	0.018uA	851mV	220.8V	0.029uA
15	840mV	220.6V	0.018uA	849mV	221.1V	0.016uA
16	840mV	217.6V	0.022uA	846mV	221.8V	0.024uA
17	844mV	221.3V	0.018uA	847mV	222.8V	0.021uA
18	855mV	221.6V	0.019uA	851mV	217.8V	0.024uA
19	841mV	219.6V	0.019uA	843mV	222.2V	0.022uA
20	856mV	217.0V	0.023uA	850mV	223.4V	0.016uA
21	856mV	216.4V	0.018uA	839mV	217.9V	0.016uA
22	847mV	216.9V	0.020uA	848mV	218.3V	0.020uA
23	844mV	219.1V	0.025uA	850mV	220.5V	0.025uA
24	848mV	221.2V	0.029uA	841mV	218.7V	0.023uA
25	852mV	219.0V	0.020uA	845mV	218.3V	0.027uA
26	856mV	217.3V	0.016uA	848mV	215.4V	0.017uA
27	840mV	217.7V	0.023uA	858mV	220.6V	0.025uA
28	841mV	216.1V	0.018uA	847mV	220.5V	0.020uA
29	855mV	219.8V	0.016uA	842mV	223.4V	0.017uA
30	841mV	219.3V	0.016uA	847mV	218.1V	0.023uA
31	846mV	217.4V	0.018uA	843mV	217.5V	0.028uA
32	852mV	218.0V	0.029uA	844mV	221.3V	0.028uA
33	858mV	219.0V	0.017uA	841mV	220.1V	0.028uA
34	854mV	217.5V	0.025uA	840mV	216.0V	0.020uA



## High Temperature High Humidity Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 85±2°C , 85±5%RH, 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	849mV	215.4V	0.024uA	857mV	217.0V	0.019uA
36	841mV	223.4V	0.023uA	846mV	223.3V	0.025uA
37	853mV	215.6V	0.018uA	846mV	221.7V	0.015uA
38	846mV	221.7V	0.016uA	845mV	216.3V	0.024uA
39	845mV	220.6V	0.028uA	857mV	216.4V	0.020uA
40	852mV	219.3V	0.027uA	847mV	220.5V	0.017uA
41	842mV	218.9V	0.022uA	854mV	220.6V	0.028uA
42	855mV	222.4V	0.029uA	857mV	222.4V	0.024uA
43	839mV	218.9V	0.028uA	857mV	217.9V	0.020uA
44	856mV	215.7V	0.017uA	842mV	216.6V	0.027uA
45	844mV	223.0V	0.024uA	854mV	219.9V	0.015uA
46	853mV	218.9V	0.023uA	849mV	217.7V	0.026uA
47	840mV	220.2V	0.023uA	851mV	219.3V	0.028uA
48	845mV	222.2V	0.024uA	842mV	222.9V	0.016uA
49	850mV	220.5V	0.028uA	843mV	218.3V	0.023uA
50	852mV	221.2V	0.022uA	853mV	219.1V	0.027uA
51	855mV	220.6V	0.025uA	849mV	222.5V	0.023uA
52	849mV	220.2V	0.019uA	842mV	218.1V	0.026uA
53	840mV	215.6V	0.023uA	845mV	216.3V	0.019uA
54	853mV	223.3V	0.018uA	839mV	221.9V	0.029uA
55	856mV	218.9V	0.022uA	850mV	220.3V	0.024uA
56	840mV	220.3V	0.025uA	841mV	218.7V	0.025uA
57	848mV	216.7V	0.020uA	844mV	223.7V	0.016uA
58	845mV	220.1V	0.022uA	854mV	219.2V	0.025uA
59	846mV	218.2V	0.018uA	854mV	223.2V	0.017uA
60	839mV	218.6V	0.021uA	850mV	215.9V	0.017uA
61	852mV	217.1V	0.022uA	855mV	222.4V	0.023uA
62	847mV	223.5V	0.020uA	846mV	215.4V	0.019uA
63	850mV	219.8V	0.029uA	846mV	223.6V	0.026uA
64	841mV	221.0V	0.026uA	845mV	222.4V	0.018uA
65	846mV	220.6V	0.027uA	844mV	220.7V	0.023uA
66	840mV	221.4V	0.019uA	858mV	216.0V	0.021uA
67	849mV	223.3V	0.020uA	857mV	221.0V	0.019uA
68	846mV	218.0V	0.016uA	850mV	219.1V	0.021uA



# SeCoS Corporation

## High Temperature High Humidity Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 85±2°C , 85±5%RH, 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	842mV	222.8V	0.018uA	839mV	219.7V	0.019uA
70	857mV	222.8V	0.027uA	855mV	219.9V	0.015uA
71	849mV	219.9V	0.023uA	843mV	218.5V	0.018uA
72	849mV	218.4V	0.018uA	840mV	221.2V	0.016uA
73	841mV	222.1V	0.028uA	842mV	221.4V	0.021uA
74	856mV	216.0V	0.016uA	847mV	219.4V	0.017uA
75	852mV	217.8V	0.017uA	853mV	217.3V	0.017uA
76	850mV	215.2V	0.023uA	856mV	217.4V	0.027uA
77	843mV	219.0V	0.018uA	846mV	221.4V	0.022uA

Made By: King Huang

Approval: Peter Yang



# SeCoS Corporation

## High Temperature High Humidity Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 85±2°C , 85±5%RH, 80% VR 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	855mV	221.4V	0.028uA	844mV	220.6V	0.024uA
2	844mV	223.0V	0.024uA	858mV	219.3V	0.029uA
3	840mV	215.9V	0.020uA	853mV	220.7V	0.018uA
4	849mV	222.0V	0.026uA	846mV	222.3V	0.026uA
5	855mV	216.2V	0.021uA	855mV	218.0V	0.024uA
6	856mV	219.7V	0.027uA	855mV	219.8V	0.024uA
7	854mV	221.0V	0.016uA	843mV	222.4V	0.026uA
8	849mV	220.9V	0.019uA	852mV	215.3V	0.025uA
9	843mV	219.7V	0.023uA	852mV	222.7V	0.018uA
10	848mV	223.2V	0.025uA	854mV	219.8V	0.025uA
11	856mV	221.0V	0.027uA	857mV	217.2V	0.022uA
12	842mV	216.6V	0.016uA	852mV	223.2V	0.025uA
13	842mV	223.5V	0.024uA	855mV	220.3V	0.017uA
14	856mV	218.7V	0.020uA	844mV	217.3V	0.016uA
15	843mV	220.9V	0.028uA	844mV	220.4V	0.019uA
16	843mV	223.2V	0.018uA	849mV	223.4V	0.026uA
17	846mV	216.3V	0.028uA	840mV	215.1V	0.026uA
18	845mV	221.7V	0.017uA	850mV	215.4V	0.015uA
19	857mV	218.5V	0.027uA	856mV	216.7V	0.020uA
20	855mV	220.6V	0.017uA	845mV	222.0V	0.028uA
21	851mV	217.8V	0.023uA	840mV	223.9V	0.021uA
22	850mV	222.9V	0.018uA	857mV	223.7V	0.026uA
23	841mV	222.0V	0.022uA	841mV	223.2V	0.018uA
24	853mV	221.4V	0.016uA	856mV	220.0V	0.027uA
25	848mV	217.7V	0.025uA	851mV	220.1V	0.019uA
26	852mV	216.3V	0.026uA	852mV	216.3V	0.016uA
27	841mV	215.8V	0.027uA	846mV	220.7V	0.018uA
28	840mV	220.8V	0.028uA	858mV	216.2V	0.029uA
29	849mV	222.4V	0.023uA	844mV	220.8V	0.020uA
30	843mV	220.7V	0.026uA	839mV	223.5V	0.018uA
31	848mV	217.3V	0.016uA	848mV	221.8V	0.020uA
32	839mV	221.0V	0.023uA	847mV	218.8V	0.017uA
33	839mV	219.4V	0.018uA	858mV	216.1V	0.016uA
34	839mV	215.3V	0.020uA	850mV	220.0V	0.028uA



## High Temperature High Humidity Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 85±2°C , 85±5%RH, 80% VR 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
35	849mV	216.5V	0.016uA	847mV	222.9V	0.021uA
36	853mV	219.9V	0.029uA	854mV	222.6V	0.017uA
37	851mV	218.1V	0.028uA	852mV	217.9V	0.020uA
38	854mV	223.9V	0.020uA	850mV	221.5V	0.028uA
39	858mV	217.0V	0.019uA	853mV	215.2V	0.021uA
40	855mV	217.1V	0.016uA	840mV	219.3V	0.023uA
41	851mV	215.3V	0.019uA	851mV	221.7V	0.022uA
42	848mV	223.2V	0.017uA	857mV	216.7V	0.018uA
43	847mV	219.0V	0.019uA	839mV	223.1V	0.020uA
44	844mV	223.2V	0.021uA	847mV	216.4V	0.019uA
45	852mV	221.1V	0.024uA	852mV	219.8V	0.024uA
46	840mV	219.3V	0.023uA	841mV	222.3V	0.020uA
47	852mV	223.8V	0.026uA	853mV	216.1V	0.029uA
48	856mV	215.3V	0.028uA	854mV	222.1V	0.022uA
49	850mV	218.9V	0.028uA	854mV	219.2V	0.015uA
50	840mV	220.8V	0.022uA	844mV	216.9V	0.024uA
51	852mV	217.6V	0.021uA	853mV	215.7V	0.018uA
52	852mV	223.2V	0.019uA	844mV	217.8V	0.015uA
53	842mV	218.5V	0.026uA	852mV	223.2V	0.026uA
54	842mV	222.8V	0.022uA	840mV	220.1V	0.029uA
55	855mV	217.3V	0.019uA	854mV	220.7V	0.017uA
56	851mV	218.2V	0.022uA	852mV	218.7V	0.017uA
57	854mV	220.9V	0.015uA	855mV	222.5V	0.028uA
58	841mV	215.3V	0.019uA	848mV	223.9V	0.023uA
59	852mV	216.4V	0.019uA	858mV	221.3V	0.017uA
60	849mV	215.5V	0.016uA	843mV	223.1V	0.016uA
61	840mV	216.9V	0.026uA	852mV	215.8V	0.027uA
62	855mV	215.9V	0.027uA	841mV	222.3V	0.021uA
63	841mV	223.7V	0.021uA	858mV	218.4V	0.017uA
64	851mV	221.2V	0.021uA	853mV	217.7V	0.028uA
65	857mV	222.9V	0.029uA	858mV	217.1V	0.024uA
66	857mV	216.1V	0.019uA	845mV	215.0V	0.026uA
67	843mV	219.6V	0.026uA	843mV	223.1V	0.028uA
68	841mV	215.8V	0.028uA	852mV	216.8V	0.025uA





# SeCoS Corporation

## High Temperature High Humidity Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 85±2°C , 85±5%RH, 80% VR 1000Hrs

Test Date: 2018.07.10 ~ 2018.08.21

Test Standard : JESD22 STANDER Method-A101

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
69	847mV	219.6V	0.017uA	841mV	218.4V	0.026uA
70	856mV	221.5V	0.026uA	857mV	216.3V	0.017uA
71	852mV	219.8V	0.016uA	846mV	216.0V	0.025uA
72	840mV	223.4V	0.021uA	856mV	221.7V	0.021uA
73	858mV	219.7V	0.018uA	842mV	220.8V	0.017uA
74	844mV	217.1V	0.019uA	840mV	219.8V	0.019uA
75	856mV	223.1V	0.023uA	849mV	222.8V	0.028uA
76	840mV	216.7V	0.022uA	850mV	216.2V	0.018uA
77	851mV	222.2V	0.016uA	842mV	218.2V	0.017uA

Made By: King Huang

Approval: Peter Yang



# SeCoS Corporation

## Solderability Test Data

Report No : T180702-8200C

Part No : SM8200C-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<910mV@IF=8A ; VBR>200V@I1=1mA

IR<50uA@VR=200V

Test Condition: 245 ± 5°C, 5Sec

Test Date: 2018.08.28

Test Standard : JESD22 STANDER Method-B102

Operator: Joe Lee

Test Result: PASS

No	Before			After		
	VF (mV)	VBR (V)	IR (uA)	VF (mV)	VBR (V)	IR (uA)
1	842mV	215.8V	0.023uA	845mV	221.3V	0.022uA
2	856mV	216.2V	0.021uA	856mV	221.3V	0.016uA
3	845mV	222.8V	0.017uA	844mV	220.3V	0.018uA
4	844mV	220.7V	0.016uA	846mV	220.3V	0.024uA
5	842mV	215.1V	0.022uA	842mV	219.8V	0.024uA
6	845mV	219.2V	0.022uA	854mV	223.8V	0.019uA
7	857mV	215.9V	0.028uA	844mV	216.8V	0.021uA
8	842mV	217.9V	0.023uA	847mV	218.6V	0.021uA
9	842mV	219.0V	0.025uA	849mV	222.8V	0.021uA
10	848mV	223.0V	0.018uA	858mV	218.4V	0.028uA

Made By: King Huang

Approval: Peter Yang